

EMC TEST REPORT

Authorized under **D**eclaration **o**f **C**onformity

According to

EN 55032: 2012+AC 2013 EN 55024 : 2010 EN 61000-3-2 : 2014 IEC 61000-4-2 : 2008

EN 61000-3-3: 2013 IEC 61000-4-3: 2006+A1:2007+A2:2010

CISPR 32 : 2012 IEC 61000-4-4 : 2012 AS/NZS CISPR 32 : 2013 IEC 61000-4-5 : 2014

IEC 61000-4-6: 2013 IEC 61000-4-8: 2009 IEC 61000-4-11: 2004

Applicant : TPV Electronics (Fujian) Co., Ltd.

Ronggiao Economic and Technological

Address : Development Zone, Fuging City, Fujian Province,

P.R. China

Equipment : LCD Monitor

*1659******* 156LM00005

Model No. : The "*" could be any alphanumeric character

including blank for marketing differentiation.

I HEREBY CERTIFY THAT:

The sample was received on Dec 03, 2016 and the testing was carried out on Dec 15 2016 at Cerpass Technology Corp. The test result refers exclusively to the test presented test model / sample. Without written approval of Cerpass Technology Corp., the test report shall not be reproduced except in full.

Cerpass Technology Corp. Issued Date : Dec 20, 2016

Page No.

: 1 of 78



EMC TEST REPORT

Issued by:

Cerpass Technology (Suzhou) Co.,Ltd

No.66, Tangzhuang Road, Suzhou Industrial Park, Jiangsu 215006, China

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The test record, data evaluation & Equipment Under Test configurations represented herein are true and accurate accounts of the measurements of the samples EMC characteristics under the conditions specified in this report.

The above equipment was tested by Cerpass Technology Corp. for compliance with the requirements of technical standards specified above under the EMC Directive. The results of testing in this report apply only to the product/system, which was tested. Other similar equipment will not necessarily produce the same results due to production tolerance and measurement uncertainties

Approved by:

Miro Chueh

EMC/RF B.U. Manager

Laboratory Accreditation:

Cerpass Technology Corporation Test Laboratory

NVLAP LAB Code: 200954-0 **TAF LAB Code:** 1439

 \boxtimes Cerpass Technology(SuZhou) Co., Ltd.

NVLAP LAB Code:	200814-0
CNAS LAB Code:	L5515

Cerpass Technology Corp. Report format Revision 01 Page No. : 2 of 78

Issued Date : Dec 20, 2016



Issued Date

Page No.

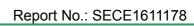
: Dec 20, 2016

: 3 of 78

Contents

1.	Summ	ary of Test Procedure and Test Results	6
2.	lmmur	nity Testing Performance Criteria Definition	7
3.	Test C	onfiguration of Equipment under Test	8
	3.1.	Feature of Equipment under Test	8
	3.2.	Test Manner	9
	3.3.	Description of Support Unit	10
	3.4.	General Information of Test	11
	3.5.	Measurement Uncertainty	
4.	Test of	f Conducted Emission	
	4.1.	Test Limit	
	4.2.	Test Procedures	
	4.3.	Typical Test Setup	
	4.4.	Measurement Equipment	
	4.5.	Test Result and Data	
	4.6.	Test Photographs of Power Port	
5.		f Radiated Emission	
	5.1.	Test Limit	
	5.2.	Test Procedures	
	5.3.	Typical Test Setup	
	5.4.	Measurement Equipment	
	5.5.	Test Result and Data (30MHz ~ 1GHz)	
	5.6.	Test Result and Data (1GHz ~ 6GHz)	
	5.7.	Test Photographs (30MHz~1GHz)	
	5.8.	Test Photographs (1GHz~6GHz)	
6.	Harmo	onics Test	
	6.1.	Limits of Harmonics Current Measurement	
	6.2.	Measurement Equipment	
	6.3.	Test Result and Data	
	6.4.	Test Photographs	
7.	•	e Fluctuations Test	
	7.1.	Test Procedure	
	7.2.	Measurement Equipment	
	7.3.	Test Result and Data	
	7.4.	Test Photographs	
8.		ostatic Discharge Immunity Test	
	8.1.	Test Procedure	
	8.2.	Test Setup for Tests Performed in Laboratory	
	8.3.	Test Severity Levels	
	8.4.	Measurement Equipment	
	8.5.	Test Result and Data	
	8.6.	Test Photographs	
9.	Radio	Frequency electromagnetic field immunity test	54





Issued Date

Page No.

: Dec 20, 2016

: 4 of 78



	9.1.	Test Procedure	54
	9.2.	Test Severity Levels	54
	9.3.	TEST SETUP	55
	9.4.	Measurement Equipment	56
	9.5.	Test Result and Data	57
	9.6.	Test Photographs	58
10.	Electri	cal Fast Transient/ Burst Immunity Test	59
	10.1.	Test Procedure	59
	10.2.	Test Severity Levels	59
	10.3.	TEST SETUP	60
	10.4.	Measurement Equipment	60
	10.5.	Test Result and Data	61
	10.6.	Test Photographs	62
11.	Surge	Immunity Test	63
	11.1.	Test Procedure	63
	11.2.	Test Severity Level	63
	11.3.	TEST SETUP	64
	11.4.	Measurement Equipment	64
	11.5.	Test Result and Data	65
	11.6.	Test Photographs	66
	C	etien Dieturkenses indused by Dadie Françoiser, Fields	
12.	Condu	ction Disturbances induced by Radio-Frequency Fields	67
12.	12.1.	Test Procedure	67
12.	12.1. 12.2.	Test Procedure	67 67
12.	12.1. 12.2. 12.3.	Test Procedure Test Severity Levels TEST SETUP	67 67
12.	12.1. 12.2. 12.3.	Test Procedure	67 67
12.	12.1. 12.2. 12.3. 12.4. 12.5.	Test Procedure Test Severity Levels TEST SETUP Measurement Equipment Test Result and Data	67 68 68
	12.1. 12.2. 12.3. 12.4. 12.5. 12.6.	Test Procedure Test Severity Levels TEST SETUP Measurement Equipment Test Result and Data Test Photographs	67686869
	12.1. 12.2. 12.3. 12.4. 12.5. 12.6.	Test Procedure Test Severity Levels TEST SETUP Measurement Equipment Test Result and Data	67686869
	12.1. 12.2. 12.3. 12.4. 12.5. 12.6. Power 13.1.	Test Procedure Test Severity Levels TEST SETUP Measurement Equipment Test Result and Data Test Photographs Frequency Magnetic Field Immunity Test Test Setup	6768697071
	12.1. 12.2. 12.3. 12.4. 12.5. 12.6. Power 13.1.	Test Procedure Test Severity Levels TEST SETUP Measurement Equipment Test Result and Data Test Photographs Frequency Magnetic Field Immunity Test	6768697071
	12.1. 12.2. 12.3. 12.4. 12.5. 12.6. Power 13.1. 13.2. 13.3.	Test Procedure Test Severity Levels TEST SETUP Measurement Equipment Test Result and Data Test Photographs Frequency Magnetic Field Immunity Test Test Setup Test Severity Levels Measurement Equipment	6768697171
	12.1. 12.2. 12.3. 12.4. 12.5. 12.6. Power 13.1. 13.2. 13.3.	Test Procedure Test Severity Levels TEST SETUP Measurement Equipment Test Result and Data Test Photographs Frequency Magnetic Field Immunity Test Test Setup Test Severity Levels	6768697171
13.	12.1. 12.2. 12.3. 12.4. 12.5. 12.6. Power 13.1. 13.2. 13.3. 13.4. 13.5.	Test Procedure Test Severity Levels TEST SETUP Measurement Equipment Test Result and Data Test Photographs Frequency Magnetic Field Immunity Test Test Setup Test Severity Levels Measurement Equipment Test Result and Data Test Result and Data Test Photographs	676869717171717171
13.	12.1. 12.2. 12.3. 12.4. 12.5. 12.6. Power 13.1. 13.2. 13.3. 13.4. 13.5. Voltage	Test Procedure Test Severity Levels TEST SETUP Measurement Equipment Test Result and Data Test Photographs Frequency Magnetic Field Immunity Test Test Setup Test Severity Levels Measurement Equipment Test Result and Data Test Result and Data Test Photographs Epips and Voltage Interruptions Immunity Test Setup	676869707171717273
13.	12.1. 12.2. 12.3. 12.4. 12.5. 12.6. Power 13.1. 13.2. 13.3. 13.4. 13.5. Voltage 14.1.	Test Procedure Test Severity Levels TEST SETUP Measurement Equipment Test Result and Data Test Photographs Frequency Magnetic Field Immunity Test Test Setup Test Severity Levels Measurement Equipment Test Result and Data Test Photographs Epips and Voltage Interruptions Immunity Test Setup Test Conditions	6768687071717171717171
13.	12.1. 12.2. 12.3. 12.4. 12.5. 12.6. Power 13.1. 13.2. 13.3. 13.4. 13.5. Voltage 14.1. 14.2.	Test Procedure Test Severity Levels TEST SETUP Measurement Equipment Test Result and Data Test Photographs Frequency Magnetic Field Immunity Test Test Setup Test Severity Levels Measurement Equipment Test Result and Data Test Photographs e Dips and Voltage Interruptions Immunity Test Setup Test Conditions TEST SETUP	67686971717171727374
13.	12.1. 12.2. 12.3. 12.4. 12.5. 12.6. Power 13.1. 13.2. 13.3. 13.4. 13.5. Voltage 14.1. 14.2.	Test Procedure Test Severity Levels TEST SETUP Measurement Equipment Test Result and Data Test Photographs Frequency Magnetic Field Immunity Test Test Setup Test Severity Levels Measurement Equipment Test Result and Data Test Photographs Epips and Voltage Interruptions Immunity Test Setup Test Conditions	67686971717171727374
13.	12.1. 12.2. 12.3. 12.4. 12.5. 12.6. Power 13.1. 13.2. 13.3. 13.4. 13.5. Voltage 14.1. 14.2. 14.3. 14.4.	Test Procedure Test Severity Levels TEST SETUP Measurement Equipment Test Result and Data Test Photographs Frequency Magnetic Field Immunity Test Test Setup Test Severity Levels Measurement Equipment Test Result and Data Test Photographs E Dips and Voltage Interruptions Immunity Test Setup Test Conditions TEST SETUP Measurement Equipment Test Result and Data	
13.	12.1. 12.2. 12.3. 12.4. 12.5. 12.6. Power 13.1. 13.2. 13.3. 13.4. 13.5. Voltage 14.1. 14.2. 14.3. 14.4. 14.5.	Test Procedure Test Severity Levels TEST SETUP Measurement Equipment Test Result and Data Test Photographs Frequency Magnetic Field Immunity Test Test Setup Test Severity Levels Measurement Equipment Test Result and Data Test Photographs e Dips and Voltage Interruptions Immunity Test Setup Test Conditions TEST SETUP Measurement Equipment	

	16
Report No.: SECE1611178	66

History of this test report

■ ORIGINAL.

 $\hfill\square$ Additional attachment as following record:

Report No	Version	Date	Description
SECE1611178	Rev 01	Dec 20, 2016	Initial Issue

Cerpass Technology Corp. Issued Date : Dec 20, 2016 Page No. : 5 of 78



CE

Report No.: SECE1611178

1. Summary of Test Procedure and Test Results

EMISSION [EN55032]				
Standard	Item	Result	Remarks	
	Conducted (Power Port)	PASS	Meet Class B Limit Minimum passing margin(AVG) is-7.99 dB at 0.4780MHz	
EN55032: 2012+AC 2013 AS/NZS CISPR 32 : 2013	Conducted (Telecom port)	N/A	N/A	
CISPR 32 : 2012	Radiated	PASS	Meets Class B Limit Minimum passing margin(QP) is -6.00 dB at 182.4500MHz	
EN 61000-3-2: 2014	Harmonic current emissions	PASS	Meet Class D Limit	
EN61000-3-3:2013	Voltage fluctuations & flicker	PASS	Meets the requirements	

IMMUNITY [EN 55024:2010]			
Standard	Item	Result	Remarks
IEC 61000-4-2: 2008	ESD	PASS	Meets the requirements of Performance Criterion A
IEC 61000-4-3: 2006+A1:2007+A2:2010	RS	PASS	Meets the requirements of Performance Criterion A
IEC 61000-4-4: 2012	EFT	PASS	Meets the requirements of Performance Criterion A
IEC 61000-4-5:2014	Surge	PASS	Meets the requirements of Performance Criterion A
IEC 61000-4-6:2013	CS	PASS	Meets the requirements of Performance Criterion A
IEC 61000-4-8:2009	PFMF	PASS	Meets the requirements of Performance Criterion A
IEC 61000-4-11:2004	Voltage dips & voltage variations	PASS	Meets the requirements of Voltage Dips: 1) >95% reduction Performance Criterion B 2) 30% reduction Performance Criterion B Voltage Interruptions: 1) >95% reduction Performance Criterion C

Cerpass Technology Corp. Issued Date : Dec 20, 2016

Report format Revision 01 Page No. : 6 of 78





2. Immunity Testing Performance Criteria Definition

Criteria A:	The apparatus shell continues to operate as intended without operator intervention. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. The performance level may be replaced by a permissible loss of performance. If the manufacturer does not specify the minimum performance level or the permissible performance loss, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.
	After test, the apparatus shell continues to operate as intended without operator intervention. No degradation of performance or loss of function is allowed, after the application of the phenomenon below a performance level specified by the manufacturer, when the apparatus is used as intended. The performance level may be replaced by a permissible loss of performance.
Criteria B:	During the test, degradation of performance is however allowed. However, no change of operating state if stored data is allowed to persist after the test. If the manufacturer does not specify the minimum performance level or the permissible performance loss, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.
Criteria C:	Temporary loss of function is allowed, provided the functions is self-recoverable or can be restored by the operation of controls by the user in accordance with the manufacturer instructions.
	Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.

Cerpass Technology Corp. Issued Date : Dec 20, 2016

Report format Revision 01 Page No. : 7 of 78





3. Test Configuration of Equipment under Test

3.1. Feature of Equipment under Test

Product Name:	LCD Monitor
Model Name:	*1659*******, 156LM00005 The "*" could be any alphanumeric character including blank for marketing differentiation.
Housing material:	Plastic case
EUT Highest Frequency:	148.5MHz

Note: Please refer to user manual.

I/O PORT:

I/O PORT TYPE	Quantity
1). USB Port	1

Issued Date : Dec 20, 2016 Cerpass Technology Corp. Page No. : 8 of 78





3.2. Test Manner

- a. During testing, the interface cables and equipment positions were varied according to Europe Standard.
- b. An executive program, "MyHwin" under Win 7, which generates a complete line of continuously repeating "H" pattern was used as the test software.

The program was executed as follows:

- 1. Turn on the power of all equipment.
- 2. The EUT reads the test program from the hard disk drive and runs it.
- 3. PC sends "H" messages to the EUT, and the monitor displays "H" patterns on the screen.
- 4. Repeat the steps from 2 to 3.
- c. The complete test system included PC, USB Keyboard, USB Mouse and EUT for EMI&EMS test.
- d. The test modes for CE/RE as follow

Test Mode 1	Full system (USB mode 1920*1080@60Hz) (110V/60Hz)
Test Mode 2	Full system (USB mode 1280*1024@75Hz) (110V/60Hz)
Test Mode 3	Full system (USB mode 640*480@60Hz) (110V/60Hz)
Test Mode 4	Full system (USB mode 1920*1080@60Hz) (230V/50Hz)
Test Mode 5	Full system (USB mode 1280*1024@75Hz) (230V/50Hz)
Test Mode 6	Full system (USB mode 640*480@60Hz) (230V/50Hz)

[&]quot;Test mode 1,4" were reported as final data.

e. The test modes for H&F/EMS as follow

Test Mode 1	Full system (USB mode 1920*1080@60Hz)
Test Mode 2	Full system (USB mode 1280*1024@75Hz)
Test Mode 3	Full system (USB mode 640*480@60Hz)

[&]quot;Test mode 1" were reported as final data.

f. The maximum operating frequency is above 108MHz, the test frequency range is from 1GHz to 6GHz.

Cerpass Technology Corp.

Report format Revision 01

Issued Date : Dec 20, 2016

: 9 of 78

Page No.





3.3. Description of Support Unit

No.	Device	Manufacturer	Model No.	Description
1	PC	HP	HP Compaq Elite 8200 MTPC	Non-Shielded ,1.8m(R33001)
2	USB Keyboard	DELL	SK-8115	N/A
3	USB Mouse	DELL	G0K02XYK	N/A

No.	Cable	Quantity	Description
Α	USB Cable	1	Shielded, 1.0m
В	USB Cable	1	Shielded, 1.8m, with one ferrite core bonded
С	USB Cable	1	Shielded, 1.2m

Cerpass Technology Corp. Issued Date : Dec 20, 2016

Page No.

: 10 of 78



3.4. General Information of Test

	T	
	Test Site	Cerpass Technology Corporation Test Laboratory Address: No.10, Ln. 2, Lianfu St., Luzhu Dist., Taoyuan City 33848, Taiwan (R.O.C.) Tel:+886-3-3226-888 Fax:+886-3-3226-881 Address: No.68-1, Shihbachongsi, Shihding Township, New Taipei City 223, Taiwan, R.O.C. Tel: +886-2-2663-8582
	FCC	TW1079, TW1061,390316, 228391, 641184
	IC	4934B-1, 4934E-1, 4934E-2
	VCCI	T-2205 for Telecommunication Test C-4663 for Conducted emission test R-3428, R-4218 for Radiated emission test G-812, G-813 for radiated disturbance above 1GHz
	Test Site	Cerpass Technology (Suzhou) Co.,Ltd Address: No.66,Tangzhuang Road, Suzhou Industrial Park, Jiangsu 215006, China Tel: +86-512-6917-5888 Fax: +86-512-6917-5666
	FCC	331395
	IC	7290A-1, 7290A-2
	VCCI	T-1945 for Telecommunication Test C-2919 for Conducted emission test R-2670 for Radiated emission test G-227 for radiated disturbance above 1GHz
Frequency F	Range Investigated:	Conducted: from 150kHz to 30 MHz Radiation: from 30 MHz to 6000MHz
Test Distanc	e :	The test distance of radiated emission below 1GHz from antenna to EUT is 10 M. The test distance of radiated emission above 1GHz from antenna to EUT is 3 M.

Cerpass Technology Corp. Issued Date : Dec 20, 2016 Page No. : 11 of 78



3.5. Measurement Uncertainty

Where relevant, the following measurement uncertainty levels have been estimated for tests performed on the EUT as specified in CISPR 16-4-2:

Measurement	Frequency	Uncertainty
Conducted emissions(LINE)	9KHz-30MHz	+/- 0.7738 dB
Conducted emissions(NEUTRAL)	9KHz-30MHz	+/- 0.7886 dB

Measurement	Polarity	Frequency	Uncertainty
	П	30MHz ~ 200MHz	+/- 3.8909dB
Radiated emissions	П	H 30MHz ~ 200MHz 200MHz ~1000MHz V 30MHz ~ 200MHz 200MHz ~1000MHz 1000MHz ~18000MHz 18000MHz ~40000MHz 1000MHz ~18000MHz	+/- 3.6555dB
(below 1GHz)	, l V	+/- 3.8948dB	
	V	200MHz ~1000MHz	+/- 3.6538dB
	Ц	1000MHz ~18000MHz	+/- 3.8948 dB
Radiated emissions	П	18000MHz ~40000MHz	+/-3.8844dB
(above 1GHz)	.,	1000MHz ~18000MHz	+/- 3.8906dB
	V	18000MHz ~40000MHz	+/- 3.8744dB

Measurement	Uncertainty
ESD—Rise time tr	10%
ESD—Peak current lp	6%
ESD—Current at 30 ns	6%
ESD—Current at 60 ns	6%
ESD- Charging voltage	1%
RS above 1GHz	±2.37dB
RS under 1GHz	±3.83dB
EFT—Rise time tr	4%
EFT—Peak current lp	4%
EFT—Current	4%
Surge—Rise time tr	4%
Surge—Peak current lp	4%

Cerpass Technology Corp. Issued Date : Dec 20, 2016 Page No. : 12 of 78



	10
Report No.: SECE1611178	75

Surge—Current	4%
CS-CND	±0.80dB
CS-Clamp	±1.06dB

This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

Consistent with industry standard (e.g. CISPR 22: 2008, clause 11, Measurement Uncertainty) determining compliance with the limits shall be base on the results of the compliance measurement. Consequently the measure emissions being less than the maximum allowed emission result in this be a compliant test or passing test.

Cerpass Technology Corp. Issued Date : Dec 20, 2016

Report format Revision 01 Page No. : 13 of 78



Report No.: SECE1611178 CE

4. Test of Conducted Emission

4.1. Test Limit

Conducted Emissions were measured from 150 kHz to 30 MHz with a bandwidth of 9 kHz and return leads of the EUT according to the methods defined in European Standard EN 55032.

Table A.8 – Requirements for conducted emissions from the AC mains power ports of Class A equipment

1. AC mai	ns power ports (3.1.1)			
Table clause	Frequency range MHz	Coupling device (see Table A.7)	Detector type / bandwidth	Class A limits dB(μV)
A8.1	0,15 - 0,5	AMM	Oversi Basalı (O.111-	79
	0,5 - 30	AMN	Quasi Peak / 9 kHz	73
A8.2	0,15 - 0,5	AMM	Average / 0 kHz	66
	0,5 - 30	AMN	Average / 9 kHz	60

Table A.9 – Requirements for conducted emissions from the AC mains power ports of Class B equipment

I. AC mai	ns power ports (3.1.1)			
Table clause	Frequency range MHz	Coupling device (see Table A.7)	Detector type / bandwidth	Class B limits dB(μV)
A9.1	0,15 - 0,5			66 – 56
	0,5 - 5	AMN	Quasi Peak / 9 kHz	56
	5 – 30			66 – 56 56 60 56 – 46
A9.2	0,15 - 0,5			56 – 46
	0,5 - 5	AMN	Average / 9 kHz	46
	5 – 30			50

Cerpass Technology Corp. Issued Date : Dec 20, 2016

Page No.

: 14 of 78



Table A.10 - Requirements for asymmetric mode conducted emissions from Class A equipment

Applicable to

- 1. wired network ports (3.1.30)
- 2. optical fibre ports (3.1.24) with metallic shield or tension members
- 3. antenna ports (3.1.3)

Table clause	Frequency range MHz	Coupling device (see Table A.7)	Detector type / bandwidth	Class A voltage limits dB(μV)	Class A current limits dB(µA)
A10.1	0,15 - 0,5	AAN	Ouesi Beek / O kHz	97 – 87	
	0,5 - 30	AAN	Quasi Peak / 9 kHz	87	2/2
	0,15 - 0,5	A A N	Average / O ld la	84 – 74	- n/a
	0,5 - 30	AAN	Average / 9 kHz	74	
A10.2	0,15 - 0,5	CVP and current probe	Quasi Peak / 9 kHz	97 – 87	53 – 43
	0,5 - 30			87	43
	0,15 - 0,5	CVP		84 – 74	40 – 30
	0,5 - 30	and current probe	Average / 9 kHz	74	30
A10.3	0,15 - 0,5	Oversont Broke	Oversi Basik / O kills		53 – 43
	0,5 - 30	Current Probe	Quasi Peak / 9 kHz	2/2	43
	0,15 - 0,5	Oversont Broke	Average / O ld la	n/a _	40 – 30
	0,5 - 30	Current Probe	Average / 9 kHz		30

- NOTE 1 The choice of coupling device and measurement procedure is defined in Annex C.
- NOTE 2 AC mains power ports shall meet the limits given in Table A.8.
- NOTE 3 The test shall cover the entire frequency range.
- NOTE 4 The application of the voltage and/or current limits is dependent on the measurement procedure used. Refer to Table C.1 for applicability.
- NOTE 5 Testing is required at only one EUT supply voltage and frequency.
- NOTE 6 Applicable to ports listed above and intended to connect to cables longer than 3 m.

Cerpass Technology Corp. Issued Date : Dec 20, 2016

Report format Revision 01

: 15 of 78

Page No.



Report No.: SECE1611178 **C E**

Table A.11 – Requirements for asymmetric mode conducted emissions from Class B equipment

Applicable to

- 1. wired network ports (3.1.30)
- 2. optical fibre ports (3.1.24) with metallic shield or tension members
- 3. broadcast receiver tuner ports (3.1.8)
- 4. antenna ports (3.1.3)

Table clause	Frequency range MHz	Coupling device (see Table A.7)	Detector type / bandwidth	Class B voltage limits dB(μV)	Class B current limits dB(µA)
A11.1	0,15 - 0,5	AAN	Overi Book / O kHz	84 – 74	n/a
	0,5 - 30	AAN	Quasi Peak / 9 kHz	74	
	0,15 - 0,5	AAN	Average / O kHz	74 – 64	
	0,5 - 30	AAN	Average / 9 kHz	64	
A11.2	0,15 - 0,5	CVP	Overi Deak / O kHz	84 – 74	40 – 30
	0,5 - 30	and current probe	Quasi Peak / 9 kHz	74	30
	0,15 - 0,5	CVP	A	74 – 64	30 – 20
	0,5 - 30	and current probe	Average / 9 kHz	64	20
A11.3	0,15 - 0,5	Current Broke	pe Quasi Peak / 9 kHz		40 – 30
	0,5 - 30	Current Probe		7/2	30
	0,15 - 0,5	Current Brok	A.,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	m/a	30 – 20
	0,5 - 30	Current Probe	Average / 9 kHz		20

- NOTE 1 The choice of coupling device and measurement procedure is defined in Annex C.
- NOTE 2 Screened ports including TV broadcast receiver tuner ports are tested with a common-mode impedance of 150 Ω . This is typically accomplished with the screen terminated by 150 Ω to earth.
- NOTE 3 AC mains power ports shall meet the limits given in Table A.9.
- NOTE 4 The test shall cover the entire frequency range.
- NOTE 5 The application of the voltage and/or current limits is dependent on the measurement procedure used. Refer to Table C.1 for applicability.
- NOTE 6 Testing is required at only one EUT supply voltage and frequency.
- NOTE 7 Applicable to ports listed above and intended to connect to cables longer than 3 m.

Cerpass Technology Corp. Issued Date : Dec 20, 2016

Page No.

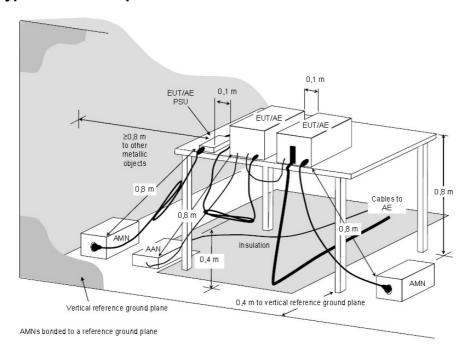
: 16 of 78



4.2. Test Procedures

- a. The EUT was placed on a desk 0.8 meters height from the metal ground plane and 0.4 meter from the conducting wall of the shielding room and it was kept at least 0.8 meters from any other grounded conducting surface.
- b. Connect EUT to the power mains through a line impedance stabilization network (LISN).
- c. All the support units are connecting to the other LISN.
- d. The LISN provides 50 ohm coupling impedance for the measuring instrument.
- e. The CISPR states that a 50 ohm, 50 micro-Henry LISN should be used.
- f. Both sides of AC line were checked for maximum conducted interference.
- g. The frequency range from 150 kHz to 30 MHz was searched
- h. Set the test-receiver system to Peak Detect Function and Specified Bandwidth with Maximum Hold Mode.

4.3. Typical Test Setup



NOTE The 0,8 m distance specified between EUT/AE/PSU and AMN/AAN, is applicable only to the EUT being measured. If the device is AE then it shall be ≥0,8 m

Figure D.2 - Example measurement arrangement for table-top EUT (Conducted emission measurement - alternative 1)

Cerpass Technology Corp. Issued Date : Dec 20, 2016 Report format Revision 01 Page No. : 17 of 78



4.4. Measurement Equipment

Instrument/Ancillary	Manufacturer	Model No.	Serial No.	Calibration Date	Valid Date.
Test Receiver	R&S	ESCI	100565	2016.07.07	2017.07.06
AMN	R&S	ESH2-Z5	100182	2016.08.31	2017.08.30
Two-Line V-Network	R&S	ENV216	100325	1	/
ISN	FCC	FCC-TLISN-T2-02	20379	2016.03.26	2017.03.25
ISN	FCC	FCC-TLISN-T4-02	20380	2016.06.24	2017.06.24
ISN	FCC	FCC-TLISN-T8-02	20381	2016.03.26	2017.03.25
ISN	TESEQ	ISN ST08	30175	2016.03.26	2017.03.25
Current Probe	R&S	EZ-17	100303	2016.03.26	2017.03.25
Passive Voltage Probe	R&S	ESH2-Z3	100026	2016.03.26	2017.03.25
Pulse Limiter	R&S	ESH3-Z2	100529	2016.03.26	2017.03.25
Temperature/ Humidity Meter	Zhicheng	ZC1-11	CEP-TH-004	2016.03.29	2017.03.28
EZ-EMC	Fala	Ver CT3A1	N/A	N/A	N/A

Cerpass Technology Corp. Issued Date : Dec 20, 2016 Page No. : 18 of 78





4.5. Test Result and Data

4.5.1 Conducted Emission for Power Port Test Data

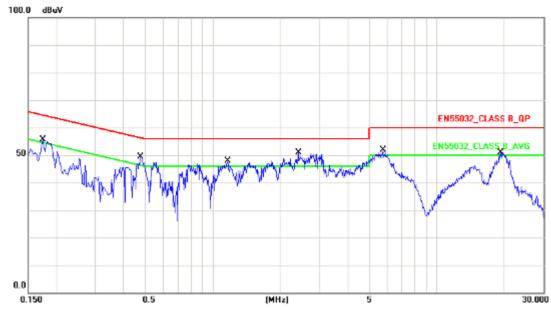
Test Mode: Mode 1: Full system (USB mode 1920*1080@60Hz)(110V/60Hz)

AC Power: AC 110V/60Hz Phase: LINE

*1659***** Equipment: LCD Monitor Model No:

25°C Temperature: Humidity: 54%

Pressure(mbar): 1001 Date: 2016/12/08



No.	Frequency	Factor	Reading	Level	Limit	Margin	Detector
	(MHz)	(dB)	(dBuV)	(dBuV)	(dBuV)	(dB)	
1	0.1740	10.13	37.97	48.10	64.76	-16.66	QP
2	0.1740	10.13	21.66	31.79	54.76	-22.97	AVG
3	0.4780	10.15	37.52	47.67	56.37	-8.70	QP
4	0.4780	10.15	28.23	38.38	46.37	-7.99	AVG
5	1.1700	10.18	32.76	42.94	56.00	-13.06	QP
6	1.1700	10.18	24.63	34.81	46.00	-11.19	AVG
7	2.4180	10.19	32.76	42.95	56.00	-13.05	QP
8	2.4180	10.19	25.27	35.46	46.00	-10.54	AVG
9	5.7740	10.26	34.56	44.82	60.00	-15.18	QP
10	5.7740	10.26	28.68	38.94	50.00	-11.06	AVG
11	19.2620	10.46	32.65	43.11	60.00	-16.89	QP
12	19.2620	10.46	25.17	35.63	50.00	-14.37	AVG

Note: Measurement Level = Reading Level + Correct Factor

Cerpass Technology Corp. Issued Date : Dec 20, 2016 Report format Revision 01 Page No. : 19 of 78



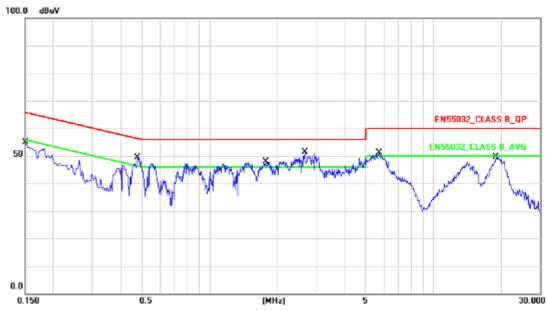
Report No.: SECE1611178

Test Mode: Mode 1: Full system (USB mode 1920*1080@60Hz)(110V/60Hz)

AC Power: AC 110V/60Hz Phase: **NEUTRAL** *1659****** Equipment: **LCD Monitor** Model No:

25°C Temperature: Humidity: 54%

Pressure(mbar): 1001 2016/12/08 Date:



No.	Frequency	Factor	Reading	Level	Limit	Margin	Detector
	(MHz)	(dB)	(dBuV)	(dBuV)	(dBuV)	(dB)	
1	0.1500	10.13	36.26	46.39	65.99	-19.60	QP
2	0.1500	10.13	8.87	19.00	55.99	-36.99	AVG
3	0.4780	10.15	37.04	47.19	56.37	-9.18	QP
4	0.4780	10.15	27.80	37.95	46.37	-8.42	AVG
5	1.7860	10.18	32.22	42.40	56.00	-13.60	QP
6	1.7860	10.18	25.43	35.61	46.00	-10.39	AVG
7	2.6780	10.19	32.77	42.96	56.00	-13.04	QP
8	2.6780	10.19	23.53	33.72	46.00	-12.28	AVG
9	5.7180	10.26	34.39	44.65	60.00	-15.35	QP
10	5.7180	10.26	28.07	38.33	50.00	-11.67	AVG
11	19.0780	10.46	31.52	41.98	60.00	-18.02	QP
12	19.0780	10.46	23.65	34.11	50.00	-15.89	AVG

Note: Measurement Level = Reading Level + Correct Factor

Cerpass Technology Corp. Issued Date : Dec 20, 2016 Page No. : 20 of 78



Report No.: SECE1611178

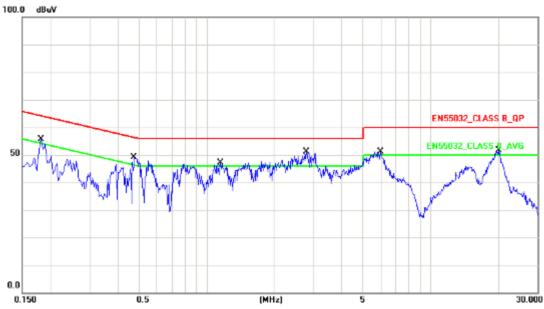
Test Mode: Mode 4: Full system (USB mode 1920*1080@60Hz)(230V/50Hz)

AC Power: AC 230V/50Hz Phase: LINE

*1659***** Equipment: **LCD Monitor** Model No:

25°C Temperature: Humidity: 54%

Pressure(mbar): 1001 2016/12/08 Date:

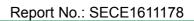


No.	Frequency	Factor	Reading	Level	Limit	Margin	Detector
	(MHz)	(dB)	(dBuV)	(dBuV)	(dBuV)	(dB)	
1	0.1819	10.13	42.00	52.13	64.39	-12.26	QP
2	0.1819	10.13	30.56	40.69	54.39	-13.70	AVG
3	0.4740	10.15	36.10	46.25	56.44	-10.19	QP
4	0.4740	10.15	23.12	33.27	46.44	-13.17	AVG
5	1.1539	10.18	33.05	43.23	56.00	-12.77	QP
6	1.1539	10.18	24.76	34.94	46.00	-11.06	AVG
7	2.7900	10.20	33.58	43.78	56.00	-12.22	QP
8	2.7900	10.20	25.46	35.66	46.00	-10.34	AVG
9	5.9899	10.26	34.15	44.41	60.00	-15.59	QP
10	5.9899	10.26	28.33	38.59	50.00	-11.41	AVG
11	20.0740	10.44	33.21	43.65	60.00	-16.35	QP
12	20.0740	10.44	26.13	36.57	50.00	-13.43	AVG

Note: Measurement Level = Reading Level + Correct Factor

Cerpass Technology Corp. Issued Date : Dec 20, 2016 Page No. : 21 of 78





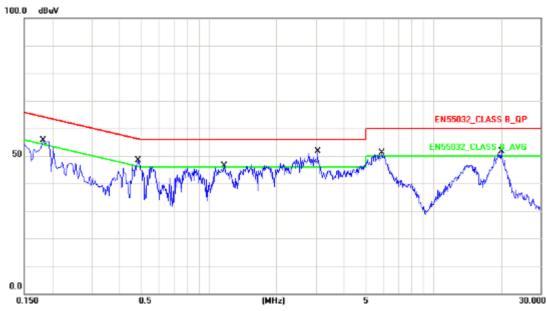
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Test Mode: Mode 4: Full system (USB mode 1920*1080@60Hz)(230V/50Hz)

AC Power: AC 230V/50Hz Phase: NEUTRAL Equipment: LCD Monitor Model No: *1659********

Temperature: 25°C Humidity: 54%

Pressure(mbar): 1001 Date: 2016/12/08



No.	Frequency	Factor	Reading	Level	Limit	Margin	Detector
	(MHz)	(dB)	(dBuV)	(dBuV)	(dBuV)	(dB)	
1	0.1819	10.13	42.36	52.49	64.39	-11.90	QP
2	0.1819	10.13	30.50	40.63	54.39	-13.76	AVG
3	0.4820	10.15	36.01	46.16	56.30	-10.14	QP
4	0.4820	10.15	27.53	37.68	46.30	-8.62	AVG
5	1.1700	10.18	32.00	42.18	56.00	-13.82	QP
6	1.1700	10.18	23.59	33.77	46.00	-12.23	AVG
7	3.0420	10.20	32.76	42.96	56.00	-13.04	QP
8	3.0420	10.20	22.88	33.08	46.00	-12.92	AVG
9	5.9100	10.26	33.82	44.08	60.00	-15.92	QP
10	5.9100	10.26	27.83	38.09	50.00	-11.91	AVG
11	20.1100	10.44	32.87	43.31	60.00	-16.69	QP
12	20.1100	10.44	25.50	35.94	50.00	-14.06	AVG

Note: Measurement Level = Reading Level + Correct Factor

Test engineer: Sun. Zhong

Cerpass Technology Corp.Issued Date: Dec 20, 2016Report format Revision 01Page No.: 22 of 78





4.5.2 Conducted Emission for Telecommunication Port Test Data

Note: The EUT doesn't have the telecommunication port.

Cerpass Technology Corp. Issued Date : Dec 20, 2016 Page No. : 23 of 78

Issued Date

: Dec 20, 2016

4.6. Test Photographs of Power Port



Front View



Rear View

Cerpass Technology Corp.

Report format Revision 01 Page No. : 24 of 78



5. Test of Radiated Emission

5.1. Test Limit

The EUT shall meet the limits of below Table when measured at the measuring distance R in accordance with the methods described in European Standard EN 55032. If the reading on the measuring receiver shows fluctuations close to the limit, the reading shall be observed for at least 15 s at each measurement frequency; the highest reading shall be recorded, with the exception of any brief isolated high reading, which shall be ignored.

Table 1 - Required highest frequency for radiated measurement

Highest internal frequency	Highest measured frequency
(F _x)	
F _x ≤ 108 MHz	1 GHz
108 MHz < F _x ≤ 500 MHz	2 GHz
500 MHz < F _x ≤ 1 GHz	5 GHz
F _x > 1 GHz	$5 \times F_{\mathbf{X}}$ up to a maximum of 6 GHz

NOTE 1 For FM and TV broadcast receivers, $F_{\rm x}$ is determined from the highest frequency generated or used excluding the local oscillator and tuned frequencies.

NOTE 2 F_x is defined in 3.1.19.

Where the F_x is unknown, the radiated emission measurements shall be performed up to 6 GHz.

Table A.2 – Requirements for radiated emissions at frequencies up to 1 GHz for Class A equipment

Table clause Frequency range	Me	asurement	Class A limits dB(μV/m)	
	MHz	Distance m	Detector type/ bandwidth	OATS/SAC (see Table A.1)
A2.1	30 – 230	40		40
	230 - 1 000	10	Quasi Peak /	47
A2.2	30 – 230		120 kHz	50
	230 - 1 000	3		57

Table A.3 – Requirements for radiated emissions at frequencies above 1 GHz for Class A equipment

Table clause Frequency range MHz	Measurement		Class A limits dB(μV/m)	
	MHz	Distance m	Detector type/ bandwidth	FSOATS (see Table A.1)
A3.1	1 000 – 3 000		Average /	56
	3 000 - 6 000	•	1 MHz	60
A3.2	1 000 – 3 000	3	Peak /	76
	3 000 - 6 000		1 MHz	80

NOTE Apply A3.1 and A3.2 across the frequency range from 1 000 MHz to the highest required frequency of measurement derived from Table 1.

Cerpass Technology Corp.Issued Date: Dec 20, 2016Report format Revision 01Page No.: 25 of 78



Table A.4 – Requirements for radiated emissions at frequencies up to 1 GHz for Class B equipment

Table clause Frequency range	Frequency range	Me	asurement	Class B limits dB(μV/m)	
	MHz	Distance m	Detector type/ bandwidth	OATS/SAC (see Table A.1)	
A4.1	30 – 230	40		30	
	230 - 1 000	10	Quasi Peak /	37	
A4.2	30 – 230	2	120 kHz	40	
	230 - 1 000	3		47	

Table A.5 – Requirements for radiated emissions at frequencies above 1 GHz for Class B equipment

Table clause	, , , ,	Me	easurement	Class B limits dB(μV/m)	
MHz	Distance m	Detector type/ bandwidth	FSOATS (see Table A.1)		
A5.1	1 000 – 3 000		Average/	50	
	3 000 - 6 000	•	1 MHz	54	
A5.2	1 000 – 3 000	3	Peak/	70	
	3 000 - 6 000		1 MHz	74	

NOTE Apply A5.1 and A5.2 across the frequency range from 1 000 MHz to the highest required frequency of measurement derived from Table 1.

Table A.6 - Requirements for radiated emissions from FM receivers

Table Frequency range		Me	asurement	Class B limit dB(μV/m)		
clause MHz	MHz	Distance	Detector type/	Fundamental	Harmonics	
		m	bandwidth	OATS/SAC (see Table A.1)	OATS/SAC (see Table A.1)	
A6.1	30 – 230				42	
	230 – 300	10	50 Quasi peak/	10	50	42
	300 – 1 000				46	
A6.2	30 – 230		120 kHz		52	
	230 – 300	3		60	52	
	300 – 1 000				56	

NOTE 1 Apply only A.6.1 or A.6.2 across the entire frequency range.

NOTE 2 These relaxed limits apply only to emissions at the fundamental and harmonic frequencies of the local oscillator. Signals at all other frequencies shall be compliant with the limits given in Table A.4.

Cerpass Technology Corp. Issued Date : Dec 20, 2016

Page No.

: 26 of 78



Table A.12 – Requirements for conducted differential voltage emissions from Class B equipment

Applicable to

- 1. TV broadcast receiver tuner ports (3.1.8) with an accessible connector
- 2. RF modulator output ports (3.1.27)
- 3. FM broadcast receiver tuner ports (3.1.8) with an accessible connector

Table clause	Frequency range	Detector type/ bandwidth	Class B limits dB(μV) 75 Ω			Applicability
	MHz		Other	Local Oscillator Fundamental	Local Oscillator Harmonics	
A12.1	30 – 950		46	46	46	See NOTE 1
	950 – 2 150	For frequencies ≤1 GHz	46	54	54	
A12.2	950 – 2 150	Quasi Peak/	46	54	54	See NOTE 2
A12.3	30 – 300	120 kHz	46	54	50	See NOTE 3
	300 – 1 000				52	
A12.4	30 – 300	For frequencies	46	66	59	See NOTE 4
	300 – 1 000	≥1 GHz			52	
A12.5	30 - 950	Peak/ 1 MHz	46	76	46	See NOTE 5
	950 – 2 150	. 141112		n/a	54	

- NOTE 1 Television receivers (analogue or digital), video recorders and PC TV broadcast receiver tuner cards working in channels between 30 MHz and 1 GHz, and digital audio receivers.
- NOTE 2 Tuner units (not the LNB) for satellite signal reception.
- NOTE 3 Frequency modulation audio receivers and PC tuner cards.
- NOTE 4 Frequency modulation car radios.
- NOTE 5 Applicable to EUTs with RF modulator output ports (for example DVD equipment, video recorders, camcorders and decoders etc.) designed to connect to TV broadcast receiver tuner ports.
- NOTE 6 Testing is required at only one EUT supply voltage and frequency.
- NOTE 7 The term 'other' refers to all emissions other than the fundamental and the harmonics of the local oscillator.
- NOTE 8 The test shall be performed with the device operating at each reception channel.
- NOTE 9 The test shall cover the entire frequency range.

Cerpass Technology Corp. Issued Date : Dec 20, 2016

Page No.

: 27 of 78



CE

5.2. Test Procedures

- a. The EUT was placed on a rotatable table top 0.8 meter above ground.
- b. The EUT was set 3/10 meters from the interference receiving antenna which was mounted on the top of a variable height antenna tower.
- c. The table was rotated 360 degrees to determine the position of the highest radiation.
- d. The antenna is a half wave dipole and its height is varied between one meter and four meters above ground to find the maximum value of the field strength both horizontal polarization and vertical polarization of the antenna are set to make the measurement.
- e. For each suspected emission the EUT was arranged to its worst case and then tune the antenna tower (from 1 M to 4 M) and turn table (from 0 degree to 360 degrees) to find the maximum reading.
- f. Set the test-receiver system to Peak Detect Function and specified bandwidth with Maximum Hold Mode.
- g. If the emission level of the EUT in peak mode was 3 dB lower than the limit specified, then testing will be stopped and peak values of EUT will be reported, otherwise, the emissions which do not have 3 dB margin will be repeated one by one using the quasi-peak method and reported.

5.3. Typical Test Setup

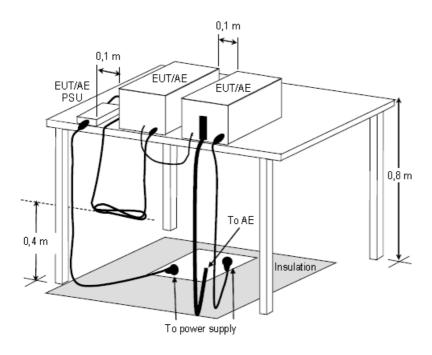


Figure D.8 – Example measurement arrangement for table-top EUT (Radiated emission measurement)

Cerpass Technology Corp. Issued Date : Dec 20, 2016

Report format Revision 01

Page No. : 28 of 78





5.4. Measurement Equipment

Instrument/Ancillary	Manufacturer	Model No.	Serial No.	Calibration Date	Valid Date.
EMI Test Receiver	R&S	ESCI7	100968	2016.07.21	2017.07.20
Preamplifier	Agilent	87405B	My39500554	2016.03.26	2017.03.25
Preamplifier	Agilent	8449B	3008A02342	2016.03.26	2017.03.25
Bilog Antenna	Sunol Science	JB1	A072414-1	2016.04.16	2017.04.15
Broad-Band Horn Antenna	Schwarzbeck	BBHA9120D	9120D-618	2016.04.16	2017.04.15
Spectrum Analyzer	R&S	FSP40	100324	2016.08.02	2017.08.01
Temperature/ Humidity Meter	Zhicheng	ZC1-11	CEP-TH-001	2016.03.29	2017.03.28
EZ-EMC	Fala	Ver CT3A1	N/A	N/A	N/A

Cerpass Technology Corp. Issued Date : Dec 20, 2016 Page No. : 29 of 78



5.5. Test Result and Data (30MHz ~ 1GHz)

Test Mode :	Mode 1: Full system (USB mode 1920*1080@60Hz)(110V/60Hz)						
AC Power :	AC 110V/60Hz	AC 110V/60Hz Ant. Polarization: Horizontal					
Equipment :	LCD Monitor	*1659******					
Temperature :	23°C	Humidity :	56%				
Pressure(mbar) :	1001	Date:	2016/12/04				



No.	Frequency	Factor	Reading	Level	Limit	Margin	Det.	Height	Azimuth
	(MHz)	(dB/m)	(dBuV)	(dBuV/m)	(dBuV/m)	(dB)		(cm)	(deg)
1	31.9400	-4.66	26.25	21.59	30.00	-8.41	peak	100	223
2	143.4900	-10.50	32.90	22.40	30.00	-7.60	peak	100	0
3	198.7800	-10.02	34.60	24.58	30.00	-5.42	peak	400	360
4	449.0400	-4.58	33.53	28.95	37.00	-8.05	peak	400	117
5	574.1699	-1.62	31.85	30.23	37.00	-6.77	peak	400	142
6	746.8300	1.01	30.12	31.13	37.00	-5.87	peak	400	298

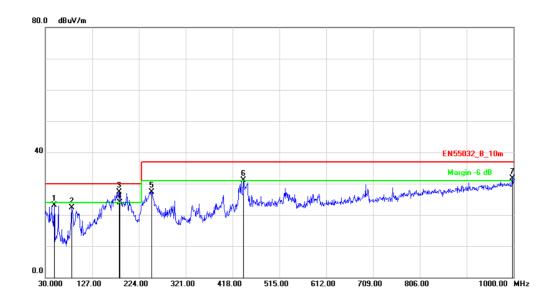
Note: Measurement Level = Reading Level + Correct Factor

Cerpass Technology Corp.Issued Date: Dec 20, 2016Report format Revision 01Page No.: 30 of 78



Report No.: SECE1611178

Test Mode :	Mode 1: Full system (U	Mode 1: Full system (USB mode 1920*1080@60Hz)(110V/60Hz)					
AC Power :	AC 110V/60Hz	AC 110V/60Hz Ant. Polarization: Vertical					
Equipment :	LCD Monitor	Model No :	*1659******				
Temperature :	23°C	Humidity :	56%				
Pressure(mbar):	1001	Date:	2016/12/04				



No.	Frequency	Factor	Reading	Level	Limit	Margin	Det.	Height	Azimuth
	(MHz)	(dB/m)	(dBuV)	(dBuV/m)	(dBuV/m)	(dB)		(cm)	(deg)
1	48.4299	-15.33	38.42	23.09	30.00	-6.91	peak	100	115
2	85.2900	-16.28	38.66	22.38	30.00	-7.62	peak	100	244
3	183.2599	-11.23	38.54	27.31	30.00	-2.69	peak	400	254
4	184.3600	-11.14	35.11	23.97	30.00	-6.03	QP	400	254
5	251.1599	-10.40	37.69	27.29	37.00	-9.71	peak	400	0
6	441.2799	-4.76	35.89	31.13	37.00	-5.87	peak	400	228
7	998.0599	4.69	27.06	31.75	37.00	-5.25	peak	100	360

Note: Measurement Level = Reading Level + Correct Factor

Cerpass Technology Corp. Issued Date : Dec 20, 2016 Page No. : 31 of 78





: Dec 20, 2016

: 32 of 78

Test Mode :	Mode 4: Full system (USB mode 1920*1080@60Hz)(230V/50Hz)						
AC Power :	AC 230V/50Hz	AC 230V/50Hz Ant. Polarization: Horizontal					
Equipment :	LCD Monitor	Model No :	*1659******				
Temperature :	23°C	Humidity :	56%				
Pressure(mbar) :	1001	Date:	2016/12/04				



No.	Frequency	Factor	Reading	Level	Limit	Margin	Det.	Height	Azimuth
	(MHz)	(dB/m)	(dBuV)	(dBuV/m)	(dBuV/m)	(dB)		(cm)	(deg)
1	32.9099	-5.36	27.02	21.66	30.00	-8.34	peak	100	226
2	143.4900	-10.50	34.08	23.58	30.00	-6.42	peak	100	314
3	198.7800	-10.02	35.05	25.03	30.00	-4.97	peak	100	0
4	450.0099	-4.55	33.02	28.47	37.00	-8.53	peak	400	88
5	586.7799	-1.43	31.07	29.64	37.00	-7.36	peak	400	269
6	698.3300	-0.18	30.27	30.09	37.00	-6.91	peak	400	0

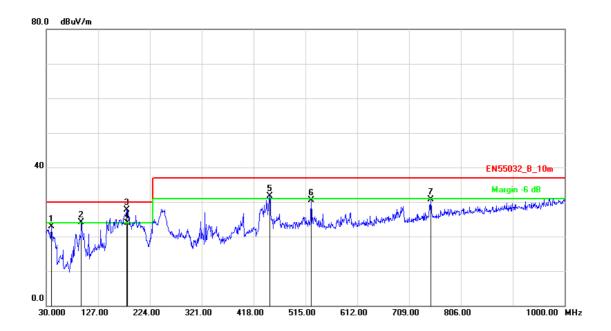
Note: Measurement Level = Reading Level + Correct Factor

Cerpass Technology Corp. Issued Date Report format Revision 01 Page No.



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Report No.: SECE1611178	6

Test Mode :	Mode 4: Full system (USB mode 1920*1080@60Hz)(230V/50Hz)						
AC Power :	AC 230V/50Hz	AC 230V/50Hz Ant. Polarization: Vertical					
Equipment :	LCD Monitor	Model No :	*1659******				
Temperature :	23°C	Humidity :	56%				
Pressure(mbar):	1001	1001 Date: 2016/12/04					



No.	Frequency	Factor	Reading	Level	Limit	Margin	Det.	Height	Azimuth
	(MHz)	(dB/m)	(dBuV)	(dBuV/m)	(dBuV/m)	(dB)		(cm)	(deg)
1	39.7000	-10.26	33.09	22.83	30.00	-7.17	peak	100	256
2	95.9599	-14.81	38.94	24.13	30.00	-5.87	peak	100	112
3	181.3199	-11.38	39.06	27.68	30.00	-2.32	peak	400	85
4	182.4500	-11.29	35.29	24.00	30.00	-6.00	QP	400	85
5	448.0699	-4.60	36.21	31.61	37.00	-5.39	peak	400	360
6	525.6699	-2.50	32.91	30.41	37.00	-6.59	peak	400	247
7	749.7400	1.08	29.63	30.71	37.00	-6.29	peak	400	42

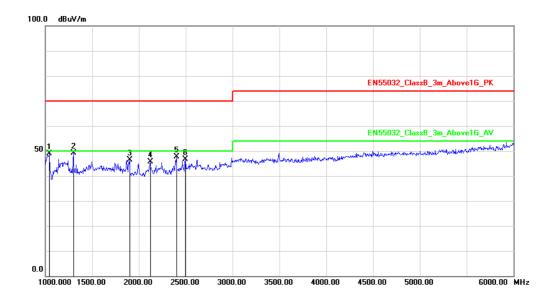
Note: Measurement Level = Reading Level + Correct Factor

Cerpass Technology Corp. Issued Date : Dec 20, 2016 Page No. : 33 of 78



5.6. Test Result and Data (1GHz ~ 6GHz)

Test Mode :	Mode 1: Full system (USB mode 1920*1080@60Hz)(110V/60Hz)					
AC Power :	AC 110V/60Hz Ant. Polarization: Horizontal					
Equipment :	LCD Monitor	*1659******				
Temperature :	23°C	Humidity :	56%			
Pressure(mbar) :	1001	Date:	2016/12/04			



No.	Frequency	Factor	Reading	Level	Limit	Margin	Det.	Height	Azimuth
	(MHz)	(dB/m)	(dBuV)	(dBuV/m)	(dBuV/m)	(dB)		(cm)	(deg)
1	1045.000	-5.68	54.65	48.97	70.00	-21.03	peak	100	336
2	1300.000	-3.98	53.17	49.19	70.00	-20.81	peak	100	211
3	1900.000	-1.49	47.89	46.40	70.00	-23.60	peak	100	155
4	2120.000	-0.59	46.10	45.51	70.00	-24.49	peak	100	0
5	2400.000	0.84	46.91	47.75	70.00	-22.25	peak	200	121
6	2495.000	1.32	45.41	46.73	70.00	-23.27	peak	200	45

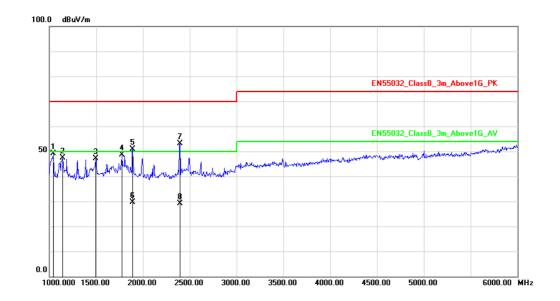
Note: Measurement Level = Reading Level + Correct Factor

Issued Date Cerpass Technology Corp. : Dec 20, 2016 Page No. : 34 of 78





Test Mode :	Mode 1: Full system (USB mode 1920*1080@60Hz)(110V/60Hz)					
AC Power :	AC 110V/60Hz	Ant. Polarization:	Vertical			
Equipment :	LCD Monitor	Model No :	*1659******			
Temperature :	23°C	Humidity :	56%			
Pressure(mbar) :	1001	Date:	2016/12/04			



No.	Frequency	Factor	Reading	Level	Limit	Margin	Det.	Height	Azimuth
	(MHz)	(dB/m)	(dBuV)	(dBuV/m)	(dBuV/m)	(dB)		(cm)	(deg)
1	1045.000	-5.68	54.88	49.20	70.00	-20.80	peak	100	245
2	1140.000	-5.04	52.40	47.36	70.00	-22.64	peak	100	15
3	1495.000	-2.67	49.92	47.25	70.00	-22.75	peak	100	0
4	1775.000	-1.85	50.52	48.67	70.00	-21.33	peak	200	328
5	1890.000	-1.52	52.39	50.87	70.00	-19.13	peak	200	177
6	1891.000	-1.51	31.14	29.63	50.00	-20.37	AVG	200	177
7	2395.000	0.81	52.35	53.16	70.00	-16.84	peak	200	22
8	2396.000	0.82	28.21	29.03	50.00	-20.97	AVG	200	22

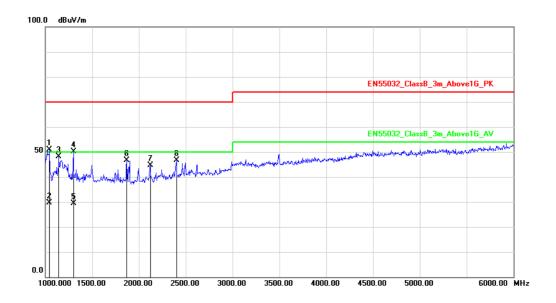
Note: Measurement Level = Reading Level + Correct Factor

Cerpass Technology Corp. Issued Date : Dec 20, 2016 Page No. : 35 of 78





Test Mode :	Mode 4: Full system (USB mode 1920*1080@60Hz)(230V/50Hz)					
AC Power :	AC 230V/50Hz	Ant. Polarization:	Horizontal			
Equipment : LCD Monitor		Model No :	*1659******			
Temperature :	23°C	Humidity :	56%			
Pressure(mbar) :	1001	Date:	2016/12/04			



No.	Frequency	Factor	Reading	Level	Limit	Margin	Det.	Height	Azimuth
	(MHz)	(dB/m)	(dBuV)	(dBuV/m)	(dBuV/m)	(dB)		(cm)	(deg)
1	1045.000	-5.68	56.65	50.97	70.00	-19.03	peak	200	186
2	1046.000	-5.67	35.23	29.56	50.00	-20.44	AVG	200	186
3	1145.000	-5.01	53.17	48.16	70.00	-21.84	peak	100	180
4	1300.000	-3.98	54.17	50.19	70.00	-19.81	peak	100	224
5	1301.000	-3.97	33.25	29.28	50.00	-20.72	AVG	100	224
6	1870.000	-1.57	48.15	46.58	70.00	-23.42	peak	100	226
7	2120.000	-0.59	45.10	44.51	70.00	-25.49	peak	100	0
8	2400.000	0.84	45.91	46.75	70.00	-23.25	peak	130	360

Note: Measurement Level = Reading Level + Correct Factor

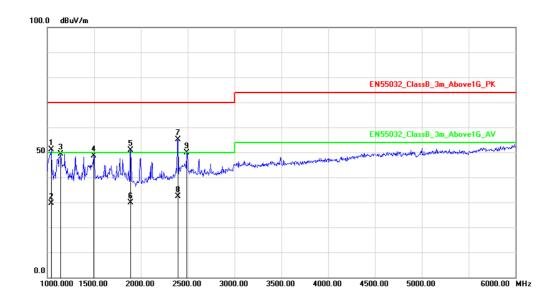
Cerpass Technology Corp. Issued Date : Dec 20, 2016 Page No. : 36 of 78



CERPASS TECHNOLOGY CORP.

	16
Report No.: SECE1611178	66

Test Mode :	Mode 4: Full system (USB mode 1920*1080@60Hz)(230V/50Hz)				
AC Power :	AC 230V/50Hz Ant. Polarization: Vertical				
Equipment :	LCD Monitor	Model No :	*1659******		
Temperature :	23°C	Humidity :	56%		
Pressure(mbar):	1001	Date:	2016/12/04		



No.	Frequency	Factor	Reading	Level	Limit	Margin	Det.	Height	Azimuth
	(MHz)	(dB/m)	(dBuV)	(dBuV/m)	(dBuV/m)	(dB)		(cm)	(deg)
1	1045.000	-5.68	56.88	51.20	70.00	-18.80	peak	100	144
2	1046.000	-5.67	35.22	29.55	50.00	-20.45	AVG	100	144
3	1140.000	-5.04	54.40	49.36	70.00	-20.64	peak	100	157
4	1495.000	-2.67	51.42	48.75	70.00	-21.25	peak	106	360
5	1890.000	-1.52	52.39	50.87	70.00	-19.13	peak	200	63
6	1892.000	-1.51	31.44	29.93	50.00	-20.07	AVG	200	63
7	2395.000	0.81	54.35	55.16	70.00	-14.84	peak	115	360
8	2396.000	0.82	31.57	32.39	50.00	-17.61	AVG	115	360
9	2490.000	1.30	48.48	49.78	70.00	-20.22	peak	100	214

Note: Measurement Level = Reading Level + Correct Factor

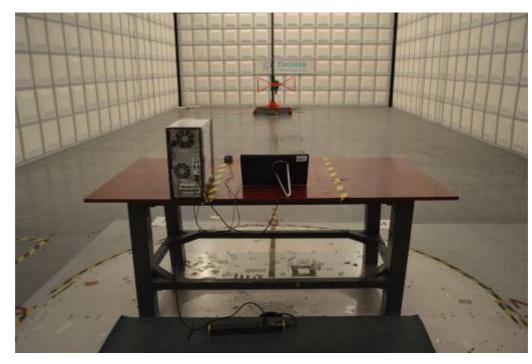
Test engineer: Sum. Zhomg

Cerpass Technology Corp.Issued Date: Dec 20, 2016Report format Revision 01Page No.: 37 of 78

5.7. Test Photographs (30MHz~1GHz)



Front View



Rear View

Cerpass Technology Corp.
Report format Revision 01

Issued Date : Dec 20, 2016

Page No. : 38 of 78

Issued Date

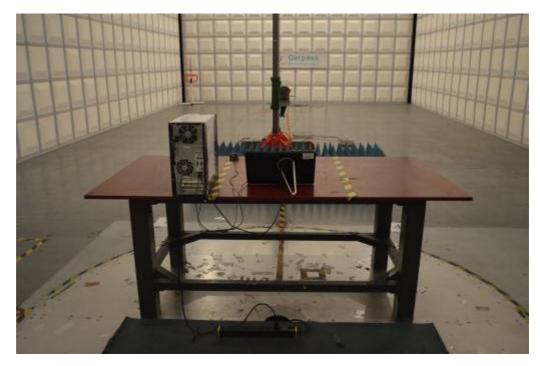
: Dec 20, 2016

CE

5.8. Test Photographs (1GHz~6GHz)



Front View



Rear View

Cerpass Technology Corp.

Report format Revision 01 Page No. : 39 of 78

6. Harmonics Test

6.1. Limits of Harmonics Current Measurement

Limits for Class A equipment

Harmonics Order n	narmonics current		Max. permissible harmonics current A
Odd h	narmonics	Even h	narmonics
3	2.30	2	1.08
5	1.14	4	0.43
7	0.77	6	0.30
9	0.40	8<=n<=40	0.23x8/n
11	0.33		
13	0.21		
15<=n<=39	0.15x15/n		

(b) Limits for Class B equipment

For Class B equipment, the harmonics of the input current shall not exceed the values given in Table that is the limit of Class A multiplied by a factor of 1,5.

(c) Limits for Class C equipment

(c) Ellillis for Olass o cquipi	Hent
Harmonics Order n	Maximum permissible harmonic current expressed as a percentage of the input current at the fundamental frequency %
2	2
3	30 · λ [*]
5	10
7	7
9	5
11 <n<39 (odd harmonics only)</n<39 	3
* λ is the circuit power factor	

(d) Limits for Class D equipment

Harmonics Order n	Maximum permissible harmonic current per watt mA/W	Maximum permissible harmonic current A
3	3.4	2.30
5	1.9	1.14
7	1.0	0.77
9	0.5	0.40
11	0.35	0.33
11 < n < 39 (odd harmonics only)	3.85/n	See limit of Class A

NOTE: According to section 7 of EN 61000-3-2, the above limits for all equipment except for lighting equipment having an active input power > 75 W and no limits apply for equipment with an active input power up to and including 75 W.

Issued Date : Dec 20, 2016 Report format Revision 01 Page No. : 40 of 78





: 41 of 78

Report No.: SECE1611178

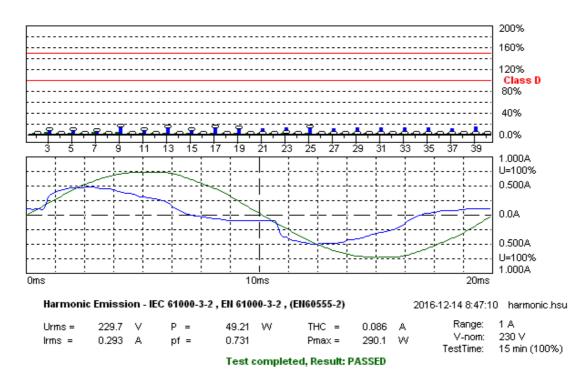
6.2. Measurement Equipment

Instrument/Ancillary	Manufacturer	Model No.	Serial No.	Calibration Date	Valid Date.
EMC Emission Tester	EMCPARTNE R	Harmonics-1000	159	2016.03.26	2017.03.25
Temperature/ Humidity Meter	Zhicheng	ZC1-11	CEP-TH-004	2016.03.29	2017.03.28
HARCS	EMC Partner	Ver 4.18	N/A	N/A	N/A
HARCS	AG	Vel 4.10	IN/A	IN/A	IN/A

Cerpass Technology Corp. Issued Date : Dec 20, 2016 Page No.

6.3. Test Result and Data

Basic Standard	:	EN 61000-3-2
Final Test Result	:	PASS
Test Mode	:	Mode 1
Model No.	:	*1659*****
Temperature	:	22 °C
Humidity	:	52%
Atmospheric Pressure	:	100 kPa
Test Date	:	Dec 14, 2016



HAR-1000 EMC-Partier

Full Bar : Actual Values
Empty Bar : Maximum Values

Blue: Current, Green: Voltage, Red: Failed

Urms = 229.7V Freq = 50.000 Range: 1 A Irms = 0.293A Ipk = 0.503A cf = 1.717P = 49.21W S = 67.30VA pf = 0.731

THDi = 29.2 % THDu = 1.10 % Class D

Test - Time: 15min (100 %) Limit Reference: Pmax = 290.13W Test completed, Result: PASSED

Cerpass Technology Corp.Issued Date: Dec 20, 2016Report format Revision 01Page No.: 42 of 78

Order Freq. Irms Irms%L Imax Imax%L [Hz] [A] [%] [A] [%]	Limit [A]
1 50 0.2809 0.2851	
2 100 0.0063 0.0066	
3 150 0.0702 7.1156 0.0710 7.1960	0.9864
4 200 0.0009 0.0010	0.5540
5 250 0.0370 6.7209 0.0375 6.8094	0.5512
6 300 0.0009 0.0010 7 350 0.0127 4.3758 0.0131 4.5020	0.2901
8 400 0.0011 0.0012	0.2901
9 450 0.0202 13.927 0.0206 14.221	0.1451
10 500 0.0013 0.0014	0.1401
11 550 0.0063 6.2511 0.0067 6.5516	0.1015
12 600 0.0011 0.0012	
13 650 0.0107 12.431 0.0109 12.644	0.0859
14 700 0.0011 0.0012	
15 750 0.0054 7.2948 0.0056 7.4587	0.0745
16 800 0.0012 0.0013	
17 850 0.0078 11.890 0.0081 12.262	0.0657
18 900 0.0010 0.0010	
19 950 0.0054 9.2400 0.0056 9.4477	0.0588
20 1000 0.0010 0.0010	
21 1050 0.0043 8.1472 0.0045 8.4914	0.0532
22 1100 0.0009 0.0010	
23 1150 0.0049 10.180 0.0051 10.431	0.0486
24 1200 0.0009 0.0010	0.0447
25 1250 0.0054 12.158 0.0056 12.431	0.0447
26 1300 0.0008 0.0009 27 1350 0.0031 7.3767 0.0033 7.9669	0.0414
27 1350 0.0031 7.3767 0.0033 7.9669 28 1400 0.0012 0.0012	0.0414
29 1450 0.0012 0.0012	0.0385
30 1500 0.0007 0.0009	0.0303
31 1550 0.0034 9.3165 0.0035 9.8247	0.0360
32 1600 0.0010 0.0012	0.0000
33 1650 0.0031 9.1963 0.0032 9.5569	0.0338
34 1700 0.0008 0.0009	0.0000
35 1750 0.0029 9.1799 0.0031 9.7537	0.0319
36 1800 0.0009 0.0009	
37 1850 0.0023 7.6827 0.0026 8.4914	0.0302
38 1900 0.0009 0.0010	
39 1950 0.0031 10.655 0.0032 11.295	0.0286
40 2000 0.0010 0.0010	

EUT is PASSED if:

- all Average values of the Individual Harmonic Currents (lavg) are below 100% of the Individual Limits.
- all Maximum values of the Individual Harmonic Currents (Imax) are below 150% of the Individual Limits.

Test engineer: Sum.

Cerpass Technology Corp.

Issued Date : Dec 20, 2016

Report format Revision 01 Page No. : 43 of 78



6.4. Test Photographs



Cerpass Technology Corp.Issued DateReport format Revision 01Page No.

Issued Date : Dec 20, 2016
Page No. : 44 of 78





7. Voltage Fluctuations Test

7.1. Test Procedure

The equipment shall be tested under the conditions of Clause 5.

The total impedance of the test circuit, excluding the appliance under test, but including the internal impedance of the supply source, shall be equal to the reference impedance.

The stability and tolerance of the reference impedance shall be adequate to ensure that the overall accuracy of $\pm 8\%$ is achieved during the whole assessment procedure.

7.2. Measurement Equipment

Instrument/Ancillary	Manufacturer	Model No.	Serial No.	Calibration Date	Valid Date.
EMC Emission Tester	EMCPARTNE R	Harmonics-1000	159	2016.03.26	2017.03.25
Temperature/ Humidity Meter	Zhicheng	ZC1-11	CEP-TH-004	2016.03.29	2017.03.28
HARCS	EMC Partner	Ver 4.18	N/A	N/A	N/A
HARCS	AG	V CI 4.10	IN/A	IN/A	IN/A

Cerpass Technology Corp. Issued Date : Dec 20, 2016

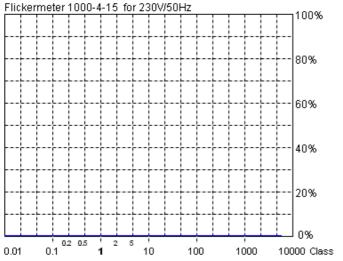
Page No.

: 45 of 78



7.3. Test Result and Data

Basic Standard	:	EN 61000-3-3
Final Test Result	:	PASS
Test Mode	:	Mode 1
Model No.	:	*1659*****
Temperature	:	22 °C
Humidity	:	52%
Atmospheric Pressure	:	100 kPa
Test Date	:	Dec 14, 2016



Actual Flicker (Fli): 0.00 Short-term Flicker (Pst): 0.07 Limit (Pst): 1.00 Long-term Flicker (Plt): 0.07 Limit (PIt): 0.65

Maximum Relative 0.00% Volt. Change (dmax): Limit (dmax): 4.00%

Relative Steady-state 0.00% Voltage Change (dc): Limit (dc): 3.30%

Maximum Interval exceeding 3.30% (dt): 0.00ms Limit (dt>Lim): 500ms

Flicker Emission - IEC 61000-3-3, EN 61000-3-3, (EN60555-3)

P = 49.70 W Urms = 229.9 V Irms = 0.295 A pf = 0.733

Test completed, Result: PASSED

2016-12-14 12:26:55 harmonic.hsu

Range: V-nom: 230 V

Page No.

: 46 of 78

TestTime: 10 min (100%)

HAR-1000 EMC-Partner

Full Bar : Actual Values **Empty Bar: Maximum Values** Circles : Average Values

Blue: Current, Green: Voltage, Red: Failed

Cerpass Technology Corp. Issued Date : Dec 20, 2016

CE

FECHNOLOGY CORP. Report No.: SECE1611178

Urms = 229.9V Freq = 50.000 Range: 1 A Irms = 0.295A Ipk = 0.508A cf = 1.722P = 49.70W S = 67.81VA pf = 0.733

Test - Time : 1 x 10min = 10min (100 %)

LIN (Line Impedance Network): No LIN

Limits: Plt: 0.65 Pst: 1.00

dmax: 4.00 % dc : 3.30 % dtLim: 3.30 % dt>Lim: 500ms

Test completed, Result: PASSED

Test engineer. Sun. Thomas

Cerpass Technology Corp.
Report format Revision 01

Issued Date : Dec 20, 2016

Page No. : 47 of 78



7.4. Test Photographs



Cerpass Technology Corp.Issued DateReport format Revision 01Page No.

Issued Date : Dec 20, 2016

: 48 of 78



8. Electrostatic Discharge Immunity Test

8.1. Test Procedure

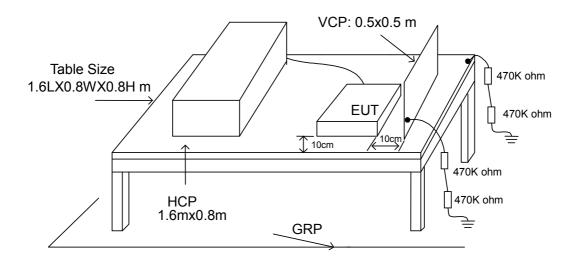
- a. In the case of air discharge testing the climatic conditions shall be within the following ranges:
 - ambient temperature: 15[°]C to 35[°]C;
 - relative humidity: 30% to 60%;
 - atmospheric pressure: 86 KPa (860 mbar) to 106 KPa (1060 mbar).
- b. Test programs and software shall be chosen so as to exercise all normal modes of operation of the EUT. The use of special exercising software is encouraged, but permitted only where it can be shown that the EUT is being comprehensively exercised.
- c. The test voltage shall be increased from the minimum to the selected test severity level, in order to determine any threshold of failure. The final severity level should not exceed the product specification value in order to avoid damage to the equipment.
- d. The test shall be performed with both air discharge and contact discharge. On reselected points at least 10 single discharges (in the most sensitive polarity) shall be applied on air discharge. On reselected points at least 25 single discharges (in the most sensitive polarity) shall be applied on contact discharge.
- e. For the time interval between successive single discharges an initial value of one second is recommended. Longer intervals may be necessary to determine whether a system failure has occurred.
- f. In the case of contact discharges, the tip of the discharge electrode shall touch the EUT before the discharge switch is operated.
- g. In the case of painted surface covering a conducting substrate, the following procedure shall be adopted:
 - If the coating is not declared to be an insulating coating by the equipment manufacturer, then the pointed tip of the generator shall penetrate the coating so as to make contact with the conducting substrate.
 - · Coating declared as insulating by the manufacturer shall only be submitted to the air discharge.
 - The contact discharge test shall not be applied to such surfaces.
- h. In the case of air discharges, the round discharge tip of the discharge electrode shall be approached as fast as possible (without causing mechanical damage) to touch the EUT. After each discharge, the ESD generator (discharge electrode) shall be removed from the EUT. The generator is then retriggered for a new single discharge. This procedure shall be repeated until the discharges are completed. In the case of an air discharge test, the discharge switch, which is used for contact discharge, shall be closed.

Cerpass Technology Corp. Issued Date : Dec 20, 2016 Page No. : 49 of 78



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8.2. Test Setup for Tests Performed in Laboratory



The test setup consists of the test generator, EUT and auxiliary instrumentation necessary to perform DIRECT and INDIRECT application of discharges to the EUT as applicable, in the follow manner:

- a. Contact Discharge to the conductive surfaces and to coupling plane;
- b. Air Discharge at insulating surfaces.

The preferred test method is that of type tests performed in laboratories and the only accepted method of demonstrating conformance with this standard. The EUT was arranged as closely as possible to arrangement in final installed conditions.

A ground reference plane was provided on the floor of the test site. It was a metallic sheet (copper or aluminum) of 0.25 mm, minimum thickness; other metallic may be used but they shall have at least 0.65 mm thickness. In the Cerpass Technology Corp., we provided 1 mm thickness stainless steel ground reference plane. The minimum size of the ground reference plane is 2.5 m x 2.5 m, the exact size depending on the dimensions of the EUT. It was connected to the protective grounding system.

The EUT was arranged and connected according to its functional requirements. A distance of 1m minimum was provided between the EUT and the wall of the lab. and any other metallic structure. In cases where this length exceeds the length necessary to apply the discharges to the selected points, the excess length shall, where possible, be placed non-inductively off the ground reference plane and shall not come closer than 0.2m to other conductive parts in the test setup.

Where the EUT is installed on a metal table, the table was connected to the reference plane via a cable with a 470k ohm resister located at each end, to prevent a build-up of charge. The test setup was consist a wooden table, 0.8m high, standing on the ground reference plane. A HCP, 1.6 m x 0.8 m, was placed on the table. The EUT and cables was isolated from the HCP by an insulating support 0.5 mm thick. The VCP size, 0.5 m x 0.5 m.

Cerpass Technology Corp. Issued Date : Dec 20, 2016

Report format Revision 01

Page No. : 50 of 78





8.3. Test Severity Levels

	Contact Discharge	Air Discharge			
Level	Test Voltage (KV) of	Level	Test Voltage (KV) of		
	Contact discharge		Air Discharge		
1	±2	1	±2		
2	±4	2	±4		
3	±6	3	±8		
4	±8	4	±15		
X Specified X Specified			Specified		
	Remark: "X" is an open level.				

8.4. Measurement Equipment

Instrument/Ancillary	Manufacturer	Model No.	Serial No.	Calibration Date	Valid Date.
ESD Simulator	EM Test	dito	V0714102399	2016.04.21	2017.04.20
Tonometer	shanghaifengyun	DYM3	3251	2015.12.21	2016.12.20
Dehumidifier	ZEDO	ZD-220LB	CEP-TH-01	N/A	N/A
Humidifier	YADU	YZ-DS251C	CEP-TH-02	N/A	N/A
Temperature/	feiyan	N/A	102	2016.03.29	2017.03.28
Humidity Meter	leiyali	IN/A	102	2010.03.29	2017.03.20

Cerpass Technology Corp. Issued Date : Dec 20, 2016 Report format Revision 01 Page No. : 51 of 78



8.5. Test Result and Data

Final Test Result : PASS

Pass performance criteria : B

Basic Standard : IEC 61000-4-2 Model No. : *1659********

Test Voltage $\begin{array}{ccc} & \pm 2 \ / \ \pm 4 \ / \ \pm 8 \ \text{KV for air discharge,} \\ & \pm 2 \ / \ \pm 4 \ \text{KV for contact discharge} \end{array}$

Temperature : 22°C
Relative Humidity : 49 %
Atmospheric Pressure : 100 kPa

Test Date : Dec 15, 2016

Test Mode: Mode 1

		Contact Discharge						Α	ir Dis	char	ge					
		times / each			times / each											
Voltage	2	kV	4	kV	6	kV	8	kV	2	kV	4	kV	8 k	ίV	10	kV
Point\Polarity	+	_	+	_	+	_	+	1	+	-	+	_	+	-	+	_
HCP	Α	Α	Α	Α												
VCP	Α	Α	Α	Α												
Screw	Α	Α	Α	Α												
Case									Α	Α	Α	Α	Α	Α		
Panel									Α	Α	Α	Α	Α	Α		
USB Port	Α	Α	Α	Α					Α	Α	Α	Α	Α	Α		

Test engineer: Sun. Zhomg

Cerpass Technology Corp. Issued Date : Dec 20, 2016

Report format Revision 01 Page No. : 52 of 78



Report No.: SECE1611178 CE

8.6. Test Photographs



Cerpass Technology Corp.

Report format Revision 01 Page No. : 53 of 78

Issued Date

: Dec 20, 2016



9. Radio Frequency electromagnetic field immunity test

9.1. Test Procedure

- a. The equipment to be tested is placed in the center of the enclosure on a wooden table. The equipment is then connected to power and signal leads according to pertinent installation instructions.
- b. The antenna which is enabling the complete frequency range of 80-1000 MHz is placed 3m away from the equipment. The required field strength is determined by placing the field strength meter(s) on top of or directly alongside the equipment under test and monitoring the field strength meter via a remote field strength indicator outside the enclosure while adjusting the continuous-wave to the applicable antennae.
- c. The test is normally performed with the antenna facing the most sensitive side of the EUT. The polarization of the field generated by the bucolical antenna necessitates testing each position twice, once with the antenna positioned vertically and again with the antenna positioned horizontally. The circular polarization of the field from the log-spiral antenna makes a change of position of the antenna unnecessary.
- d. At each of the above conditions, the frequency range is swept 80-1000 MHz, pausing to adjust the R.F. signal level or to switch oscillators and antenna. The rate of sweep is in the order of 1.5*10-3 decades/s. The sensitive frequencies or frequencies of dominant interest may be discretely analyzed.

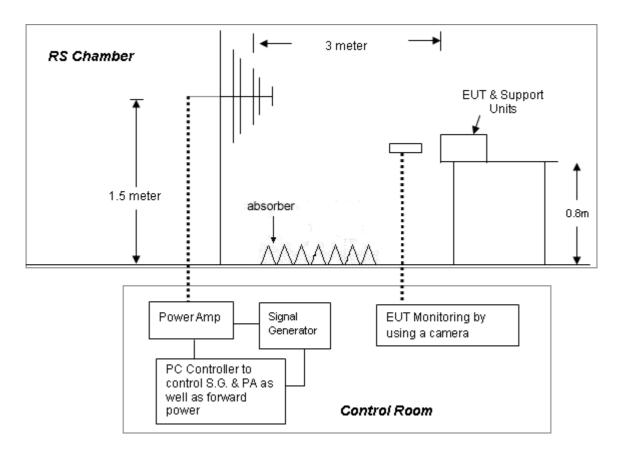
9.2. Test Severity Levels

Frequency Band : 80-1000 MHz				
Level	Test field strength (V/m)			
1	1			
2	3			
3	10			
X	Specified			
Remark: "X" is an open class.				

Cerpass Technology Corp. Issued Date : Dec 20, 2016 Page No. : 54 of 78



9.3. TEST SETUP



 For the actual test configuration, please refer to the related item – Photographs of the Test Configuration.

NOTE:

TABLETOP EQUIPMENT

The EUT installed in a representative system as described in section 7 of IEC 61000-4-3 was placed on a non-conductive table 0.8 meters in height. The system under test was connected to the power and signal wire according to relevant installation instructions.

FLOOR STANDING EQUIPMENT

The EUT installed in a representative system as described in section 7 of IEC 61000-4-3 was placed on a non-conductive wood support 0.1 meters in height. The system under test was connected to the power and signal wire according to relevant installation instructions.

Cerpass Technology Corp. Issued Date : Dec 20, 2016

Page No.

: 55 of 78





9.4. Measurement Equipment

Instrument/Ancillary	Manufacturer	Model No.	Serial No.	Calibration Date	Valid Date.
Signal Generator	R&S	SML03	103287	2016.03.26	2017.03.25
Power Sensor	R&S	NR P-Z91	100383	2016.03.26	2017.03.25
Power Sensor	R&S	NRP-Z91	100384	2016.03.26	2017.03.25
Power Meter	R&S	NRP	101206	2016.03.26	2017.03.25
Power Amplifer	BONN	BLWA0830-16 0/100/40D	076659	2016.03.26	2017.03.25
Istropic Electric Field Probe	EST.LINDGRE N	HI-6105	137445	2016.11.20	2017.11.19
EMS Antenna	R&S	HL046E	100028	N/A	N/A
Temperature/ Humidity Meter	feiyan	N/A	101	2016.03.29	2017.03.28
EMC-32	Rohde&Schwa rz	Ver 6.10.0	N/A	N/A	N/A

Cerpass Technology Corp. Issued Date : Dec 20, 2016 Page No. : 56 of 78





9.5. Test Result and Data

Final Test Result : PASS

Pass performance criteria : A

Basic Standard : IEC 61000-4-3 : *1659****** Model No.

Frequency Range : 80~1000 MHz

: 22°C Temperature : 53% Relative Humidity Atmospheric Pressure : 100 kPa

Test Date : Dec 15, 2016

Test Mode: Mode 1

Modulation: AM 80%, 1KHz sine wave , Dwell time: 3.0 S

Frequency Step Size: 1 % of preceding frequency value

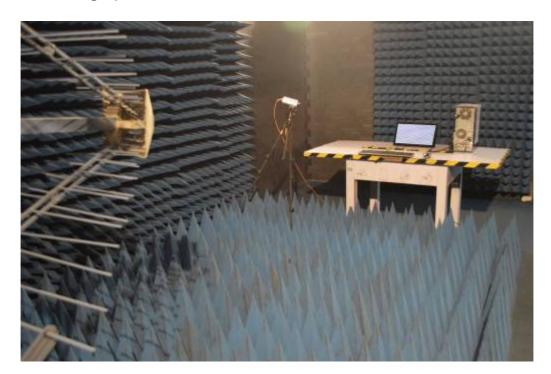
requeries step size . 1 70 or preceding frequeries value					
Frequency (MHz)	Antenna Polarization	face	Field strength (V/m)	Result	
80~1000	Vertical	Front	3 V/m	Α	
80~1000	Vertical	Rear	3 V/m	Α	
80~1000	Vertical	Left	3 V/m	Α	
80~1000	Vertical	Right	3 V/m	Α	
80~1000	Horizontal	Front	3 V/m	Α	
80~1000	Horizontal	Rear	3 V/m	Α	
80~1000	Horizontal	Left	3 V/m	Α	
80~1000	Horizontal	Right	3 V/m	Α	

Test engineer: Sun. Zhong

Cerpass Technology Corp. Issued Date : Dec 20, 2016 Page No. : 57 of 78



9.6. Test Photographs



Cerpass Technology Corp.
Report format Revision 01

Page No. : 58 of 78

: Dec 20, 2016

Issued Date



10. Electrical Fast Transient/ Burst Immunity Test

10.1. Test Procedure

- a. In order to minimize the effect of environmental parameters on test results, the climatic conditions when test is carrying out shall comply with the following requirements:
 - ambient temperature: 15[°]C to 35[°]C;
 - relative humidity: 45% to 75%;
 - Atmospheric pressure: 86 Kpa (860 mbar) to 106 Kpa (1060 mbar).
- b. In order to minimize the effect of environmental parameters on test results, the electromagnetic environment of the laboratory shall not influence the test results.
- c. The variety and diversity of equipment and systems to be tested make it difficult to establish general criteria for the evaluation of the effects of fast transients/bursts on equipment and systems.
- d. Test on Power Line:
 - The EFT/B-generator was located on the GRP. For floor standing equipment 1,0 m For table top equipment 0,5 m
 - The EFT/B-generator provides the ability to apply the test voltage in a non-symmetrical condition to the power supply input terminals of the EUT.
- e. Test on Communication Lines
 - The coupling clamp is composed of a clamp unit for housing the cable (length more than 3 m), and was placed on the GRP.
 - The coupling clamp provides the ability of coupling the fast transient/bursts to the cable under test.
- f. The test results may be classified on the basic of the operating conditions and the functional specification of the equipment under test, according to the following performance criteria:
 - Normal performance within the specification limits.
 - Temporary degradation or loss of function or performance which is self-recoverable.
 - Temporary degradation or loss of function or performance which requires operator intervention or system reset.
 - Degradation or loss of function which is not recoverable due to damage of equipment (components).

10.2. Test Severity Levels

The following test severity levels are recommended for the fast transient/burst test:

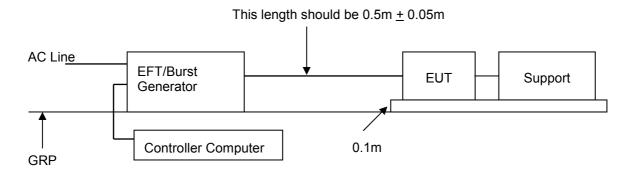
	Open circuit output test voltage \pm 10%					
Level	On Power Supply	On I/O signal, data and control line				
1	0.5 KV	0.25 KV				
2	1.0 KV	0.50 KV				
3	2.0 KV	1.00 KV				
4	4.0 KV	2.00 KV				
X	Specified	Specified				

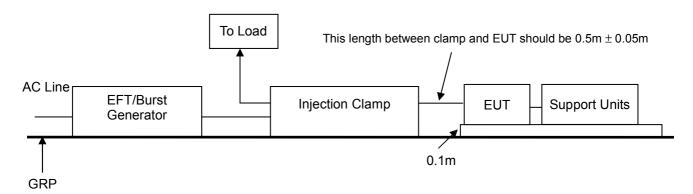
Remark: "X" is an open level. The level is subject to negotiation between the user and manufacturer or is specified by the manufacturer.

Issued Date : Dec 20, 2016 Report format Revision 01 Page No. : 59 of 78



10.3. TEST SETUP





For the actual test configuration, please refer to the related item – Photographs of the Test Configuration.

NOTE:

TABLETOP EQUIPMENT

The configuration consisted of a wooden table (0.1m high) standing on the Ground Reference Plane. The GRP consisted of a sheet of aluminum (at least 0.25mm thick and 2.5m square) connected to the protective grounding system. A minimum distance of 0.5m was provided between the EUT and the walls of the laboratory or any other metallic structure.

FLOOR STANDING EQUIPMENT

The EUT installed in a representative system as described in section 7 of IEC 61000-4-4 and its cables, were isolated from the Ground Reference Plane by an insulating support that is 0.1-meter thick. The GRP consisted of a sheet of aluminum (at least 0.25mm thick and 2.5m square) connected to the protective grounding system.

10.4. Measurement Equipment

Instrument/Ancillary	Manufacturer	Model No.	Serial No.	Calibration Date	Valid Date.
TRANSIENT	EMCPARTNER	TRA2000IN6	901	2016.06.26	2017.06.25
CDN	EMCPARTNER	CDN2000-06-32	121	2016.03.26	2017.03.25
Coupling clamp	EMCPARTNER	CN-EFT1000	547	2016.03.26	2017.03.25
Temperature/ Humidity	Zhicheng	ZC1-11	CEP-TH-005	2016.03.29	2017.03.28
Meter					

Issued Date : Dec 20, 2016 Report format Revision 01 Page No. : 60 of 78

10.5. Test Result and Data

Final Test Result : PASS Pass performance criteria : B

Basic Standard : IEC 61000-4-4 : *1659****** Model No.

On Power Supply -- ±1.0 kV

Test Voltage

On I/O signal, data and control line -- ±0.5 kV

Temperature 22°C : 54 % **Relative Humidity** Atmospheric Pressure : 100 kPa

Test Date : Dec 15, 2016

Test Mode: Mode 1

Pulse: 5/50 ns Repetition Rate: 5 kHz

Burst: 15m/300ms

Test time: 1 min/each condition

Voltage/ Mode/ Polarity/ Result/ Phase		<u>0.5 kV</u>		<u>1.0 kV</u>	
		+	_	+	_
	L			Α	Α
	N			А	Α
	L-N			А	Α
Power Line	PE			Α	Α
	L-PE			Α	Α
	N-PE			Α	Α
	L-N-PE			Α	Α

Test engineer: Sun. Zhomg

Cerpass Technology Corp. Issued Date : Dec 20, 2016 Report format Revision 01 Page No. : 61 of 78



Issued Date

: Dec 20, 2016





Cerpass Technology Corp.

Report format Revision 01 Page No. : 62 of 78



Report No.: SECE1611178 CE

11. Surge Immunity Test

11.1. Test Procedure

a. Climatic conditions

The climatic conditions shall comply with the following requirements:

- \bullet relative humidity : 10 % to 75 %
- atmospheric pressure : 86 kPa to 106 kPa (860 mbar to 1060 mbar)
- b. Electromagnetic conditions

the electromagnetic environment of the laboratory shall not influence the test results.

- c. The test shall be performed according the test plan that shall specify the test set-up with
 - generator and other equipment utilized;
 - test level (voltage/current);
 - · generator source impedance;
 - internal or external generator trigger;
 - number of tests: at least five positive and five negative at the selected points;
 - repetition rate: maximum 1/min.
 - inputs and outputs to be tested;
 - · representative operating conditions of the EUT;
 - sequence of application of the surge to the circuit;
 - phase angle in the case of AC. power supply;
 - actual installation conditions, for example :
 - AC: neutral earthed,

DC: (+) or (-) earthed to simulated the actual earthing conditions.

- d. If not otherwise specified the surges have to be applied synchronized to the voltage phase at the zero-crossing and the peak value of the AC. voltage wave (positive and negative).
- e. The surges have to be applied line to line and line(s) and earth. When testing line to earth, the test voltage has to be applied successively between each of the lines and earth, if there is no other specification.
- f. The test procedure shall also consider the non-linear current-voltage characteristics of the equipment under test. Therefore the test voltage has to be increased by steps up to the test level specified in the product standard or test plan.
- g. All lower levels including the selected test level shall be satisfied. For testing the secondary protection, the output voltage of the generator shall be increased up to the worst-case voltage breakdown level (let-through level) of the primary protection.
- h. If the actual operating signal sources are not available, that may be simulated. Under no circumstances may the test level exceed the product specification. The test shall be carried out according to a test plan.
- i. To find all critical points of the duty cycle of the equipment, a sufficient number of positive and negative test pulses shall be applied. For acceptance test previously unstressed equipment shall be used to the protection devices shall be replaced.

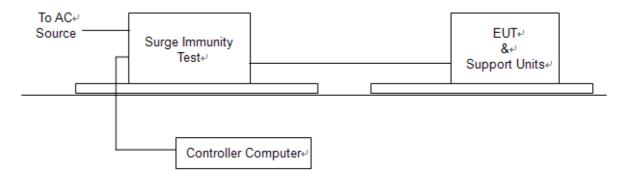
11.2. Test Severity Level

Level	Open-circuit test voltage, ± 10%, KV			
1	0.5			
2	1.0			
3	2.0			
4	4.0			
Х	Specified			
NOTE: "X" is an open class. This level can be specified in the product specification.				

Cerpass Technology Corp.Issued Date: Dec 20, 2016Report format Revision 01Page No.: 63 of 78



11.3. TEST SETUP



For the actual test configuration, please refer to the related item – Photographs of the Test Configuration.

11.4. Measurement Equipment

Instrument/Ancillary	Manufacturer	Model No.	Serial No.	Calibration Date	Valid Date.
TRANSIENT	TESEQ	NSG 3060	1830	2016.02.04	2017.02.03
CDN	TESEQ	CDN 3061	1575	2016.02.04	2017.02.03
CDN	TESEQ	CNV508T5	P 1546167499	2016.02.17	2017.02.16
CDN	TESEQ	CDN HSS-2	41020	2016.02.24	2017.02.23
Temperature/ Humidity Meter	Zhicheng	ZC1-11	CEP-TH-005	2016.03.29	2017.03.28

Cerpass Technology Corp. Issued Date : Dec 20, 2016 Page No. : 64 of 78



11.5. Test Result and Data

Final Test Result : PASS

Pass performance criteria : B

Basic Standard : IEC 61000-4-5 : *1659****** Model No.

Input AC Power Port -- ±0.5/1.0 kV for Line to Line Test Voltage

 $\pm 0.5/1.0/2.0$ kV for Line to Ground

: 22°C Temperature Relative Humidity : 54 % Atmospheric Pressure : 100 kPa

Test Date : Dec 15, 2016

Test Mode: Mode 1

Waveform : 1.2/50μs(8/20μs) Repetition rate : 60 sec Time : 20 time/each condition						
/Phase Voltage / Mode / Polarity / Result			0°	90°	180°	270°
0.5/1.0 kV		+	Α	Α	Α	А
<u>0.5/1.0</u> KV	L-N	_	Α	Α	Α	Α
	L-PE	+	Α	Α	Α	Α
0.5/1.0/2.0k//	L-PC	_	Α	Α	Α	Α
<u>0.5/1.0/2.0</u> kV -	N DE	+	Α	Α	Α	Α
	N-PE	_	Α	Α	Α	Α

Test engineer Sun. Zhomg

Cerpass Technology Corp. Issued Date : Dec 20, 2016 : 65 of 78

Report format Revision 01 Page No.



11.6. Test Photographs



Cerpass Technology Corp. Issued Date : Dec 20, 2016 : 66 of 78

Report format Revision 01 Page No.





12. Conduction Disturbances induced by Radio-Frequency Fields

12.1. Test Procedure

- a. The EUT shall be operated within its intended climatic conditions. The temperature and relative humidity should be recorded.
- b. This test method test can be performed without using a sell shielded enclosure. This is because the disturbance levels applied and the geometry of the setups are not likely to radiated a high amount of energy, especially at the lower frequencies. If under certain circumstances the radiated energy is too high, a shielded enclosure has to be used.
- c. The test shall be performed with the test generator connected to each of the coupling and decoupling devices in turn while the other non-excited RF-input ports of the coupling devices are terminated by a 50 ohm load resistor.
- d. The frequency range is swept from 150 KHz to 80 MHz, using the signal levels established during the setting process, and with the disturbance signal 80% amplitude modulated with a 1KHz sign wave, pausing to adjust the RF-signal level or to switch coupling devices as necessary. The rate of sweep shall no exceed 1.5 x 10⁻³ decades/s. Where the frequency is swept incrementally, the step size shall no exceed 1% of the start and thereafter 1% of the preceding frequency value.
- e. The dwell time at each frequency shall not be less than the time necessary for the EUT to be exercised, and able to respond. Sensitive frequencies e.g. clock frequency (ies) and harmonics or frequencies of dominant interest shall be analyzed separately.
- f. An alternative test procedure may be adopted, wherein the frequency range is swept incrementally, with a step size not exceeding 4% of the start ad thereafter 4% of the preceding frequency value. The test level should be at least twice the value of the specified test level.
- g. In cases of dispute, the test procedure using a step size not exceeding 1% of the start and thereafter 1% of preceding frequency value shall take precedence.
- h. Attempts should be made to fully exercise the EUT during testing, and to fully interrogate all exercise modes selected for susceptibility.
- i. The use of special exercising programs is recommended.
- j. Testing shall be performed according to a Test Plan, which shall be included in the test report.
- k. It may be necessary to carry out some investigatory testing in order to establish some aspects of the test plan.

12.2.Test Severity Levels

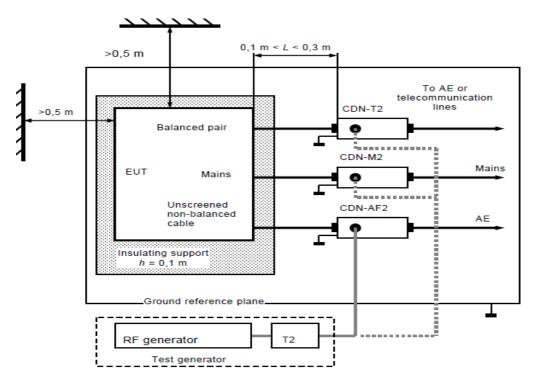
Level	Voltage Level (e.m.f.)				
1	1 V				
2	3 V				
3	10 V				
Х	Specified				
NOTE - x is an open cla	ss. This level can be specified in the product specification.				

Cerpass Technology Corp.Issued Date: Dec 20, 2016Report format Revision 01Page No.: 67 of 78

Issued Date

: Dec 20, 2016

12.3.TEST SETUP



Note: 1. The EUT is setup 0.1m above Ground Reference Plane

- 2. The CDNs and $\dot{}$ or EM clamp used for real test depends on ports and cables configuration of EUT.
- 3. For the actual test configuration, please refer to the related item Photographs of the Test Configuration.

12.4.Measurement Equipment

Instrument/Ancillary	Manufacturer	Model No.	Serial No.	Calibration Date	Valid Date.
Conducted immunity test system	FRANKONIA	CIT-10/75	102D1294	2016.03.26	2017.03.25
EM Injection clamp	FCC	F-203I-23MM	536	2016.03.26	2017.03.25
CDN	FRANKONIA	CDN-T2	A3010029	2016.03.26	2017.03.25
CDN	FRANKONIA	CDN-T4	A3015017	2016.03.26	2017.03.25
CDN	FRANKONIA	CDN-T8	A3022010	2016.03.26	2017.03.25
CDN	FRANKONIA	CDN-M2	A3002037	2016.03.26	2017.03.25
CDN	FRANKONIA	CDN-M2+M3	A3011102	2016.03.26	2017.03.25
CDN	FCC	CDN-M5/32	A3013024	2016.03.26	2017.03.25
6 dB Attenuator	FRANKONIA	N/A	N/A	2016.03.26	2017.03.25
Temperature/ Humidity Meter	Zhicheng	ZC1-11	CEP-TH-005	2016.04.02	2017.04.01
EN61000-4-6	Hubert GmbH	Ver 2.21	N/A	N/A	N/A

Cerpass Technology Corp.

Report format Revision 01 Page No. : 68 of 78



12.5. Test Result and Data

Final Test Result : PASS

Pass performance criteria : A

Basic Standard : IEC 61000-4-6 Model No. : *1659********

CDN-(M2+M3) for AC power ports

Coupling mode : CDN-T4 for signal ports

EM-Clamp for signal ports

Temperature : 22°C

Relative Humidity : 54 %

Atmospheric Pressure : 100 kPa

Test Date : Dec 15, 2016

Test Mode: Mode 1

Frequency: 0.15~80MHz, Modulation: AM 80%,1KHz sine wave, Dwell time: 3.0s

Frequency Step Size: 1 % of preceding frequency value

Frequency	Test mode	Voltage(V)	Result
0.15 ~ 80MHz	Power(M3)	3	А

Test engineer: Sum. Zhomg

Cerpass Technology Corp. Issued Date : Dec 20, 2016

Report format Revision 01 Page No. : 69 of 78



12.6. Test Photographs



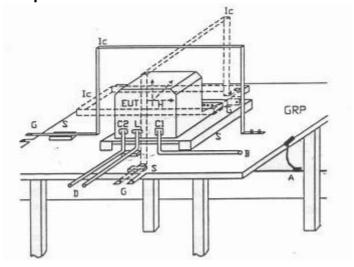
Cerpass Technology Corp. Issued Date : Dec 20, 2016 Page No. : 70 of 78





13. Power Frequency Magnetic Field Immunity Test

13.1. Test Setup



GPR : Ground plane C1 Power supply circuit

Safety earth C2 Signal circuit

Communication line Insulating support L Equipment under test EUT : В To power supply source Lc Induction coil D To signal source, simulator

Earth terminal Ε G To the test generator

13.2. Test Severity Levels

Level	Magnetic field strength (A/m)						
1	1						
2	3						
3	10						
4	30						
5	100						
X ¹⁾	special						
NOTE 1 "X" is an op	NOTE 1 "X" is an open level. This level can be given in the product specification.						

13.3. Measurement Equipment

Instrument/Ancillary	Manufacturer	Model No.	Serial No.	Calibration Date	Valid Date.
TRANSIENT	EMCPARTNER	TRA2000IN6	901	2016.06.26	2017.06.25
H-Filed-Loop	EMCPARTNER	MF1000-1	144	2016.03.26	2017.03.25
Temperature/ Humidity Meter	Zhicheng	ZC1-11	CEP-TH-005	2016.03.29	2017.03.28

Cerpass Technology Corp. Issued Date : Dec 20, 2016 Page No. : 71 of 78







13.4. Test Result and Data

Final Test Result : PASS

Pass performance criteria : A

Basic Standard : IEC 61000-4-8 Model No. : *1659*******

Temperature : 22°C
Relative Humidity : 54 %
Atmospheric Pressure : 100 kPa

Test Date : Dec 15, 2016

Test Mode: Mode 1

Power Frequency Magnetic Field : 50 Hz, 1 A/m							
Coil Orientation	Testing duration	Results					
X-axis	1.0 Min	А					
Y-axis	1.0 Min	А					
Z-axis	1.0 Min	А					
Power	Frequency Magnetic Field : 60	<u>) Hz, _1 A/m</u>					
Coil Orientation	Testing duration	Results					
X-axis	1.0 Min	А					
Y-axis	1.0 Min	А					
Z-axis	1.0 Min	А					

Test engineer: Sun. Zhomg

Issued Date : Dec 20, 2016

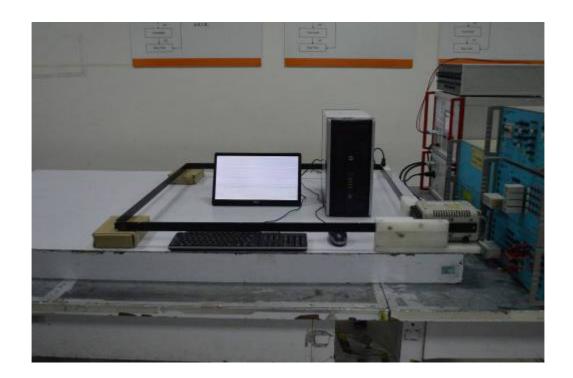
Page No. : 72 of 78







13.5. Test Photographs



Cerpass Technology Corp. Issued Date : Dec 20, 2016 Page No. : 73 of 78



14. Voltage Dips and Voltage Interruptions Immunity Test Setup

14.1. Test Conditions

1. Source voltage and frequency: AC 100/230/240V / 50Hz, Single phase.

2. Test of interval: 10 sec.

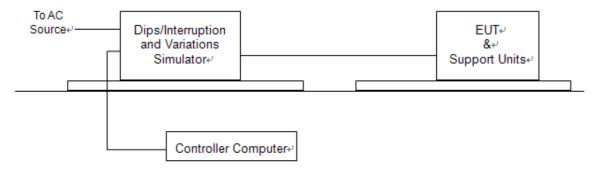
3. Level and duration: Sequence of 3 dips/interrupts.

4. Voltage rise (and fall) time : $1 \sim 5 \mu s$.

5. Test severity:

Voltage dips and Interrupt	Test Duration
reduction (%)	(period)
>95%	250
30%	25
>95%	0.5

14.2. TEST SETUP



For the actual test configuration, please refer to the related item – Photographs of the Test Configuration.

14.3. Measurement Equipment

Instrument/Ancillary	Manufacturer	Model No.	Serial No.	Calibration Date	Valid Date.
TRANSIENT	EMCPARTNER	TRA2000IN6	901	2016.06.26	2017.06.25
Temperature/ Humidity Meter	Zhicheng	ZC1-11	CEP-TH-005	2016.03.29	2017.03.28

Cerpass Technology Corp. Issued Date : Dec 20, 2016 Report format Revision 01 Page No. : 74 of 78



14.4. Test Result and Data

Final Test Result : PASS

Pass performance Criteria : C for voltage interruption, B for voltage dips

Basic Standard : IEC 61000-4-11

: *1659****** Model No.

: 22°C Temperature : 54 % Relative Humidity

Atmospheric Pressure : 100 kPa

Test Date : Dec 15, 2016

Test Mode: Mode 1

Voltage(UT): AC 230 V/240V 50 Hz Interval(s): 10s Times: 3										
	Table	Durations	Phase / Result							
Test mod	Test level UT %	(period / ms)	0	45	90	135	180	225	270	315
Voltage interruptions	>95%	250	C	С	C	С	С	С	С	С
	30%	25	Α	Α	Α	Α	Α	Α	Α	Α
Voltage dips	>95%	0.5	Α	Α	Α	Α	Α	Α	Α	Α

Test Mode: Mode 1

Voltage(UT): AC 10	00 V 50 Hz	Interval(s): 10	s T	mes :	3					
	Test level	Durations		Phase / Result						
Test mod	UT %	(period / ms)	0	45	90	135	180	225	270	315
Voltage interruptions	>95%	250	С	С	С	С	С	С	С	С
Voltage dips	30%	25	В	В	В	В	В	В	В	В
	>95%	0.5	В	В	В	В	В	В	В	В

Sun. Thomas

Cerpass Technology Corp. Issued Date : Dec 20, 2016 Page No. : 75 of 78



14.5. Test Photographs



Cerpass Technology Corp. Issued Date : Dec 20, 2016 Page No. : 76 of 78



15. Photographs of EUT

1) EUT Photo



2) EUT Photo



Cerpass Technology Corp.

Issued Date : Dec 20, 2016 Report format Revision 01 Page No. : 77 of 78





Issued Date

: Dec 20, 2016



3) EUT Photo



Cerpass Technology Corp.

Report format Revision 01 Page No. : 78 of 78